

*Micky RAKOTONDRABE, Cédric Clévy, Ioan Alexandru Ivan and Nicolas Chaillet, FEMTO-ST (Besançon, France)*

- **1** – FEMTO-ST and SAMMI group activities
- **2** – Observer techniques applied to piezocantilevers
- **3** – Self sensing of piezocantilevers



*microPAdS - FP7-PEOPLE-2007-2-1-IEF*

## Talk 1: Observer techniques applied to the control of piezoelectric microactuators

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The roots of our activity comes from **Watchmakers** industry in Besançon area & **Automotive** industry in Belfort area.

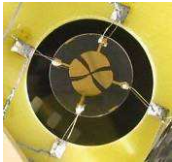
- **A wide range of technical competencies in ENGINEERING SCIENCES**
- **A MULTIDISCIPLINARY** research institute
- **A high level MICROFABRICATION TECHNOLOGY** facility
- **A culture of INNOVATION** : from basic research to industrial partnership

. 500 staff people  
 . 28 M€ annual overall budget including 10 M€ operational budget  
 . About 250 running research contracts

6 research departments  
 6 main application fields  
 1 microfabrication center



## TIME & FREQUENCY



- High-stability oscillators
- Acousto-electronics and piezoelectricity
- Time-frequency metrology

## AUTOMATIC CONTROL & MICRO-MECHATRONIC SYSTEMS (AS2M)



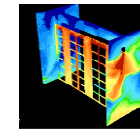
- Automatic control
- Microrobotics
- Micromechatronics
- Micromanipulation and micro-assembly
- E-maintenance and design activity guidance

## OPTICS

- Photonics and telecommunications
- Nano-optics
- Optoelectronics
- Non-linear optics
- Biophotonics

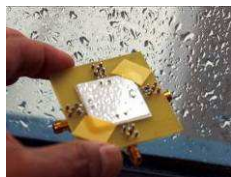


## ENERGY & MULTIPHYSICAL SYSTEMS



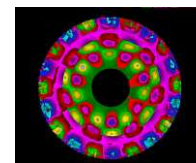
- Energy metrology and modelling
- Energy system design
- Radio protection and medical physics

## MICRO NANO SCIENCES & SYSTEMS

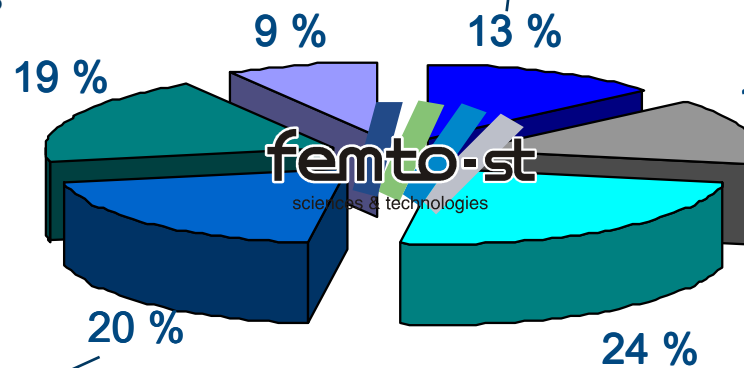


- Micro and nano-instrumentation
- Nanosciences
- Micro & Nano-acoustics
- Multiphysical Microsystems
- Micro, Nanomaterials and surfaces

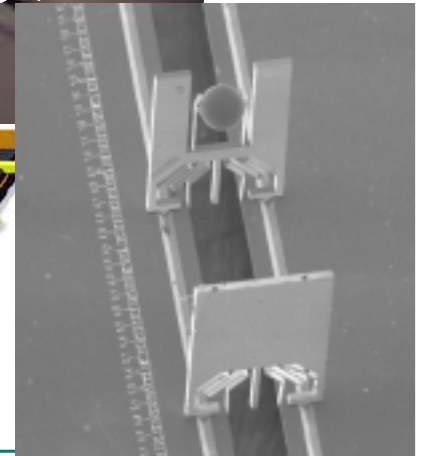
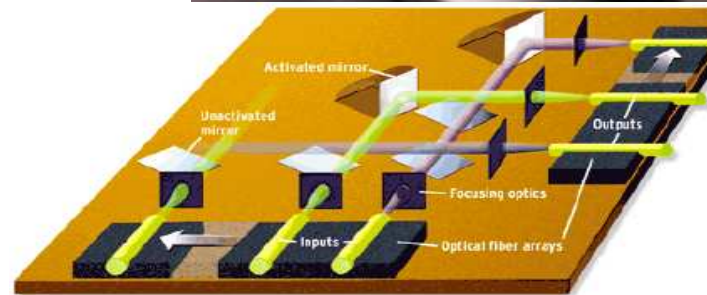
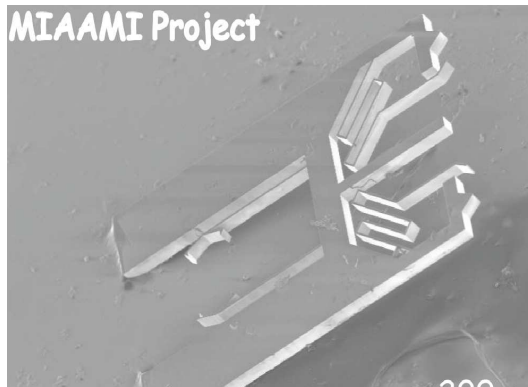
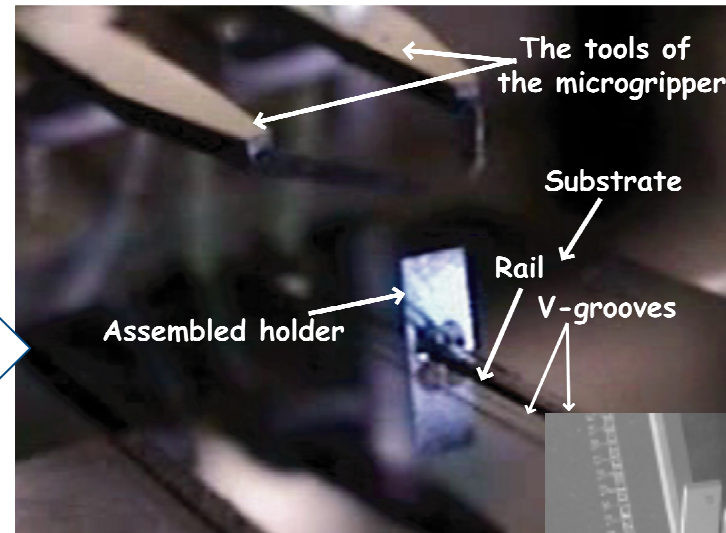
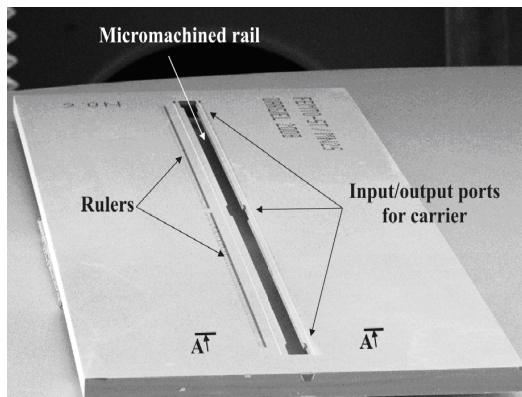
## APPLIED MECHANICS



- Mechanical properties of materials
- Structural dynamics
- Material forming and microfabrication
- Surface microanalysis



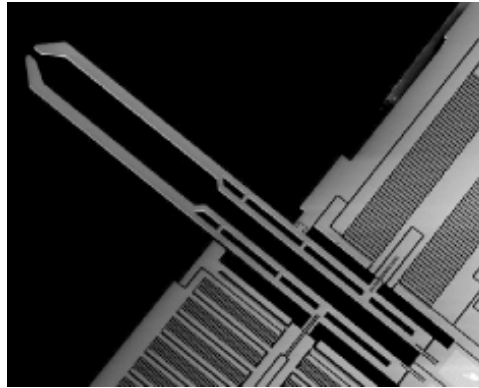
- **General objectives (1)**
  - **Create microrobots and microrobotic cells for flexible micromanipulation and microassembly**  
*Because of the growing number of microproducts to assemble, efficient and reliable micromanipulation systems are required*



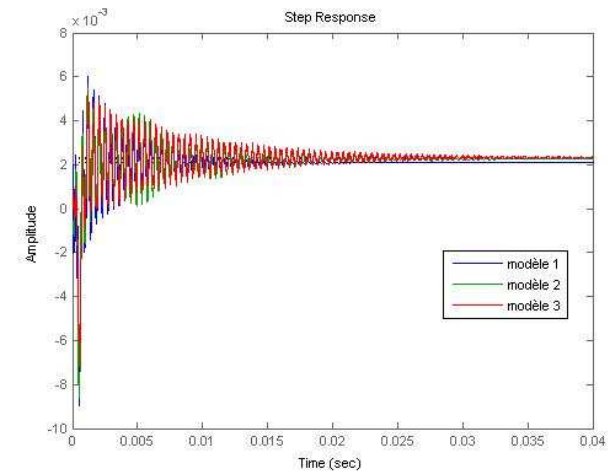
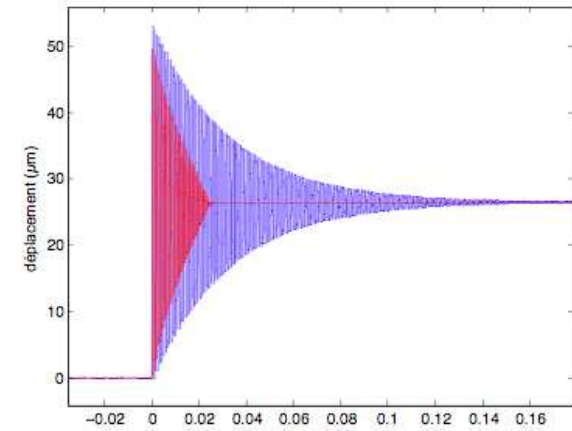
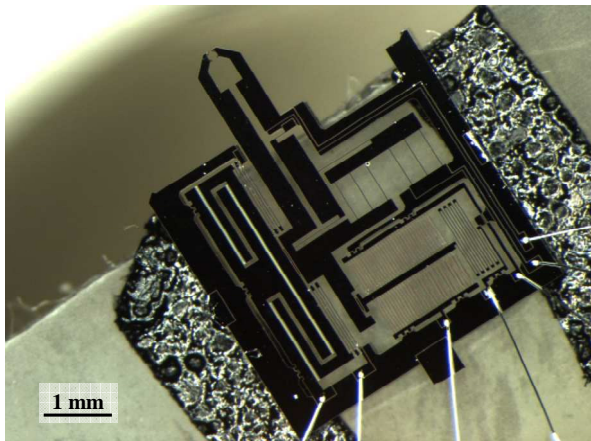
- General objectives (2)
  - Control complex microsystems  
*MEMS = specific paradigms for control science*



Microgripper from Femto-tools (FT G100)



Nanotweezer from LIMMS



## Main addressed scientific issues on control in the SAMMI group/ FEMTO-ST

### Modelling and control of:

- micro-actuators: SMA, MSMA, piezo, thermal...
- microrobots: stick slip actuation, digital MEMS,...
- discrete distributed systems: smart surface
- continuous distributed systems
- assembly microfactories: calibration, information data modelling and management



**Need of measurement (sensors, observers)**

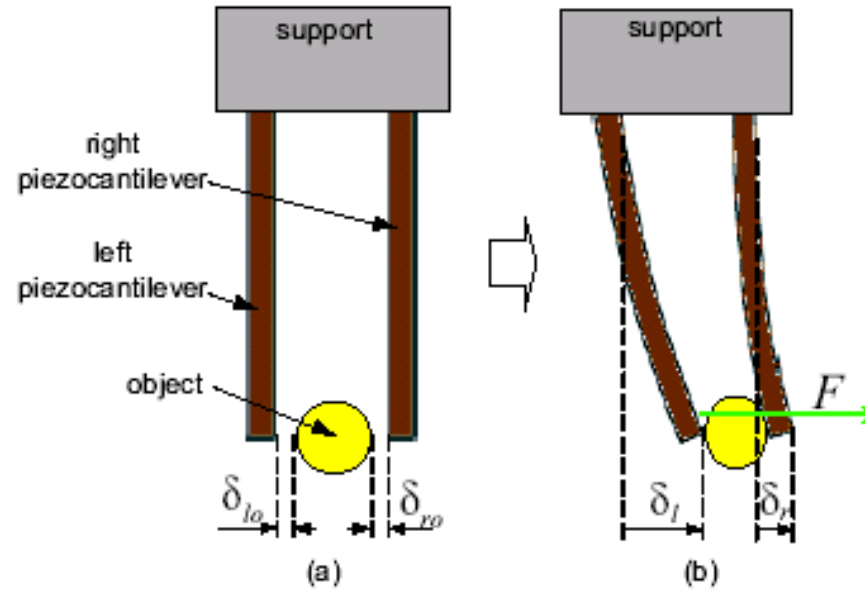
## Talk 1: Observer techniques applied to the control of piezoelectric microactuators

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- 2 – Observer techniques applied to piezocantilevers
- 3 – Self sensing of piezocantilevers

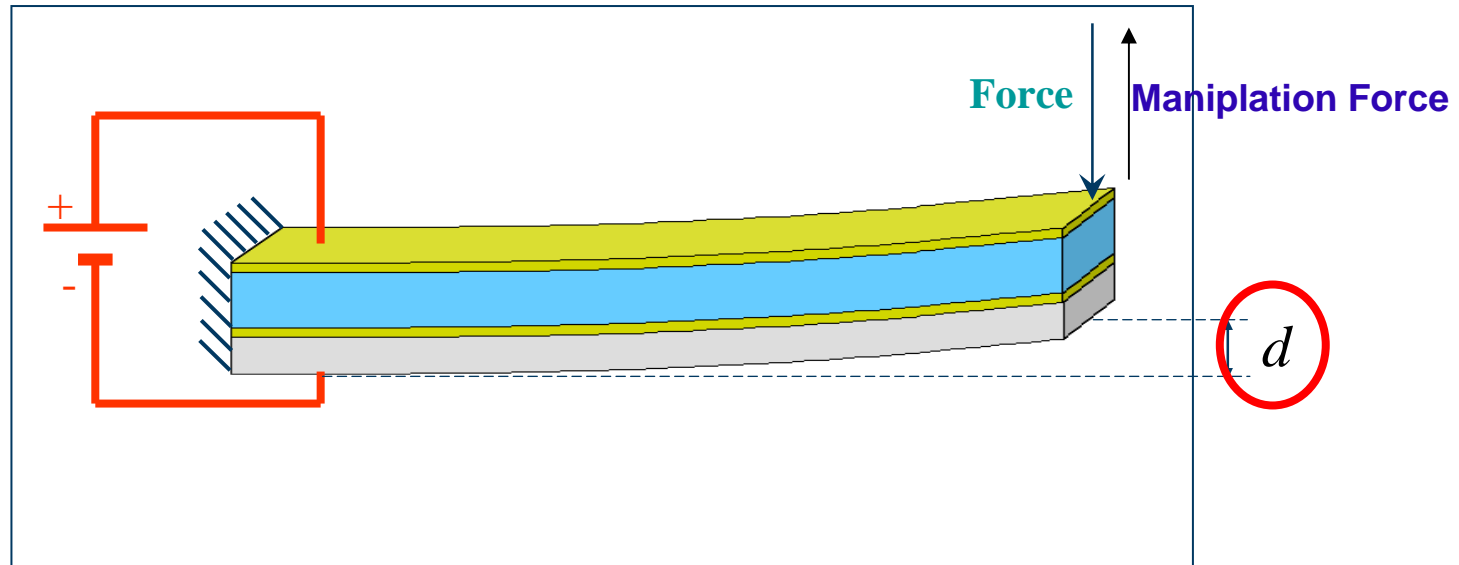


### A - Context



- Position control of one cantilever,
- Force control of the second cantilever

### A - Context



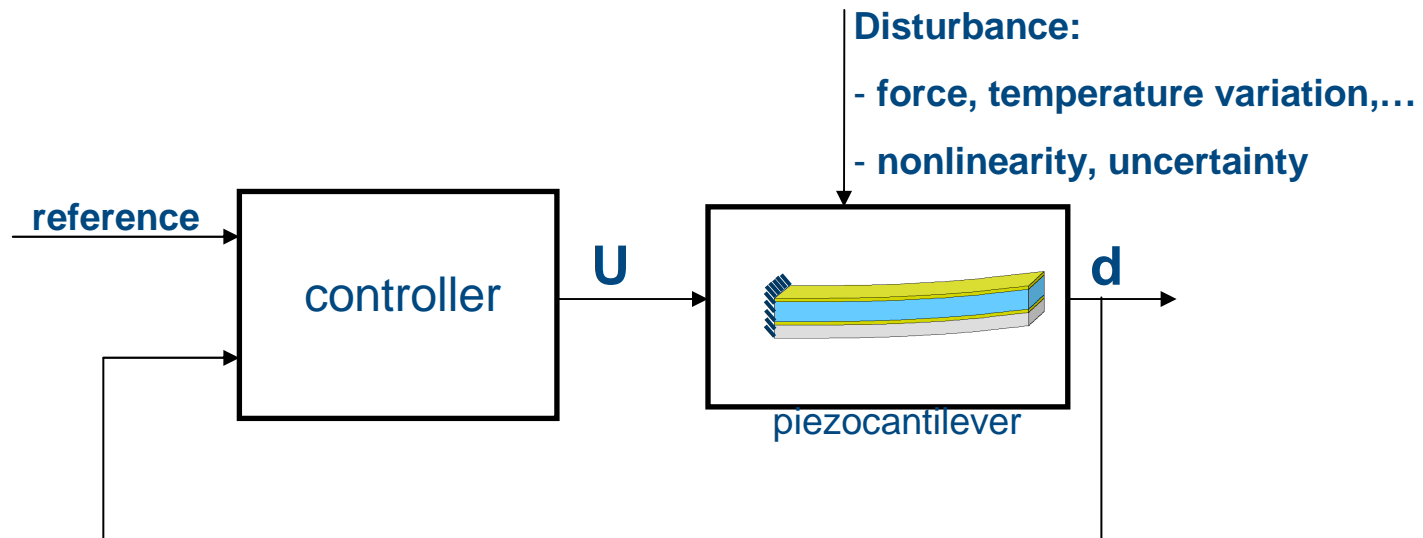
Deflection:

- Modeling,
- Control,
- Measurement/estimation

Manipulation force:

- Modeling,
- Control,
- Measurement/estimation

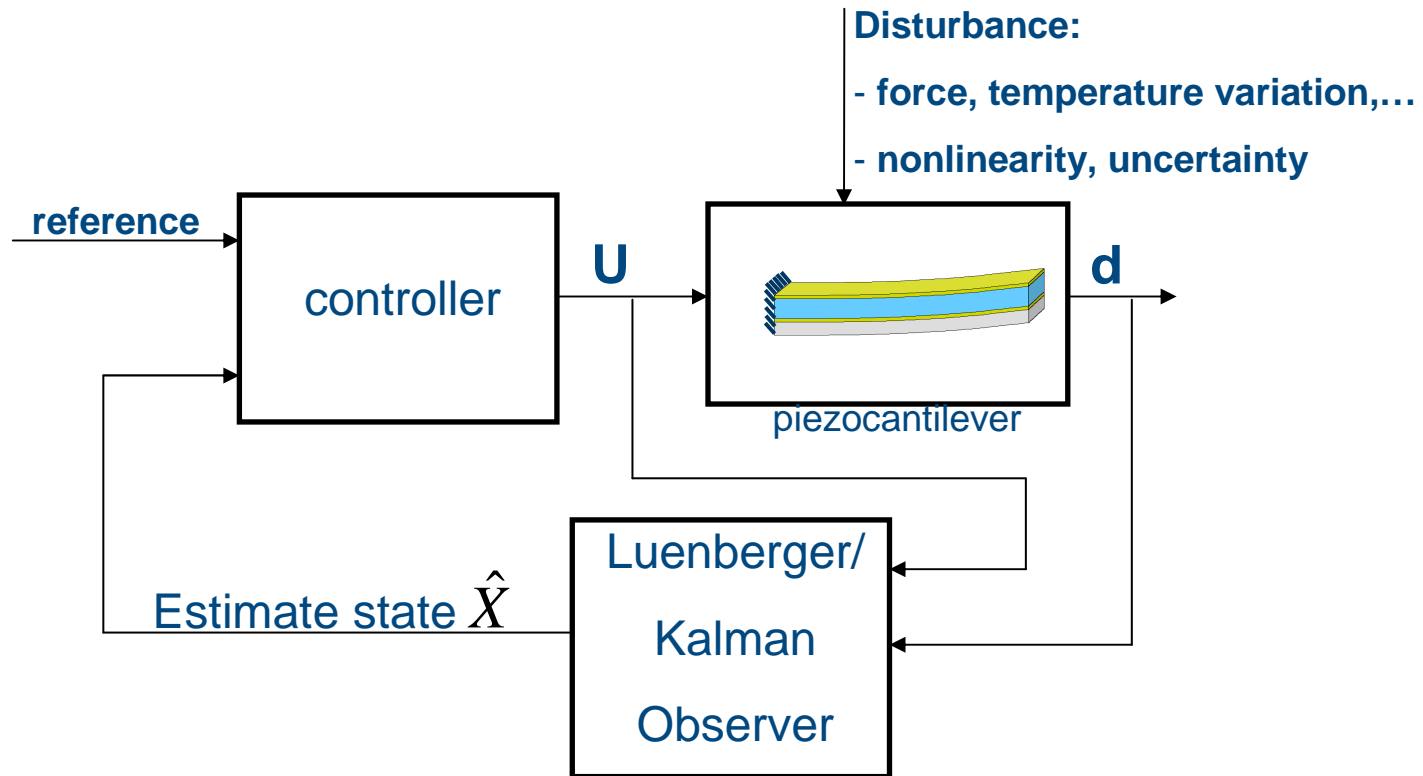
### B - Deflection measurement and control



- Frequential controller (H-inf, PID, RST...)

[CASE07]  
[IROS07]  
[ieeeTCST09]

### B - Deflection measurement and control

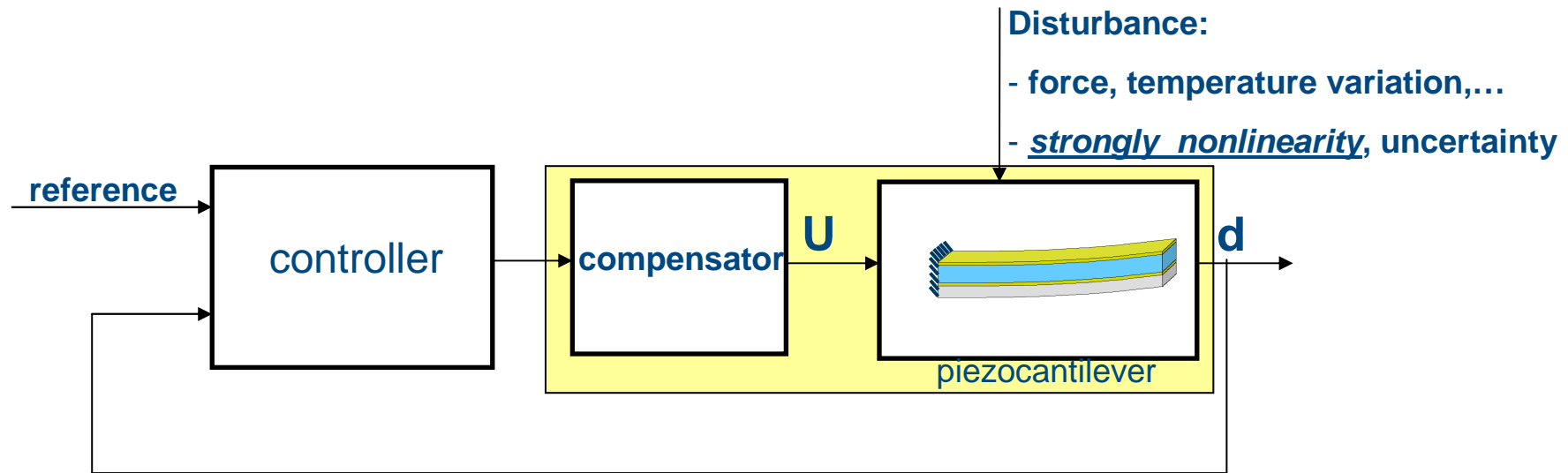


$$\frac{d\hat{X}}{dt} = A\hat{X} + BU + K_o(d - \hat{d})$$

[Haddab, PhD00]

- State-Space domain (LQ, modal control, pole assignment)

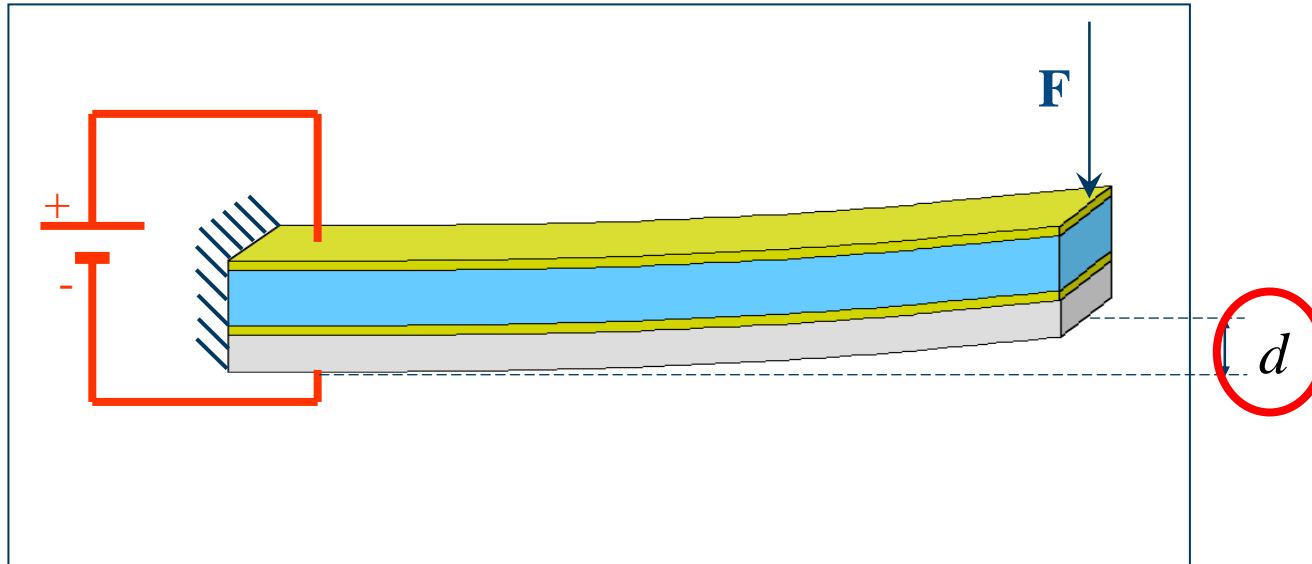
### B - Deflection measurement and control



Linearization of the nonlinearity (hysteresis and creep)

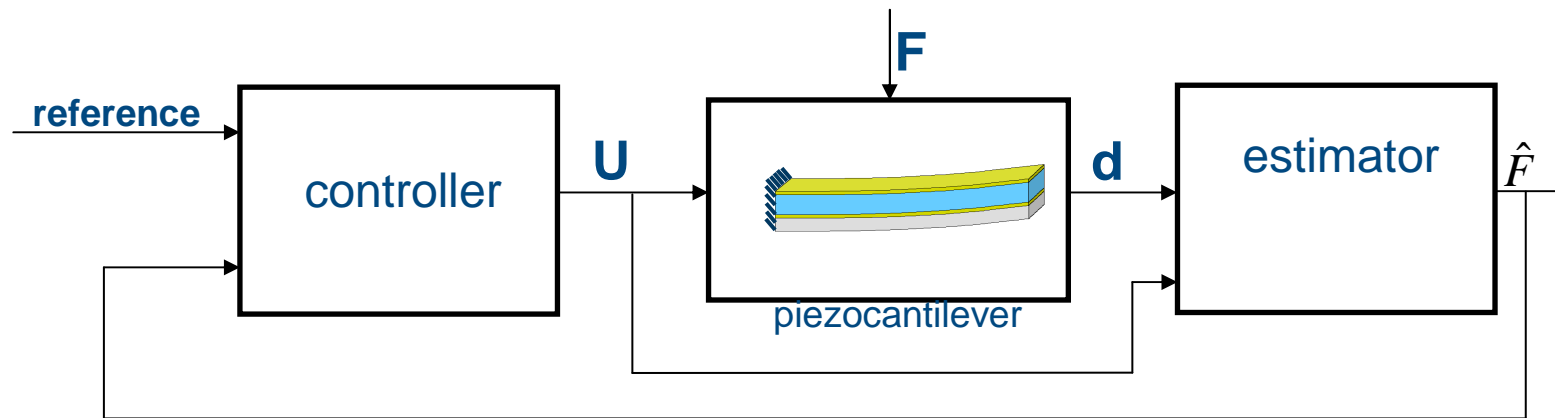
[ifacWC08]  
[ieeetasea]

### C - Force measurement and control



Information on the force: from the deflection

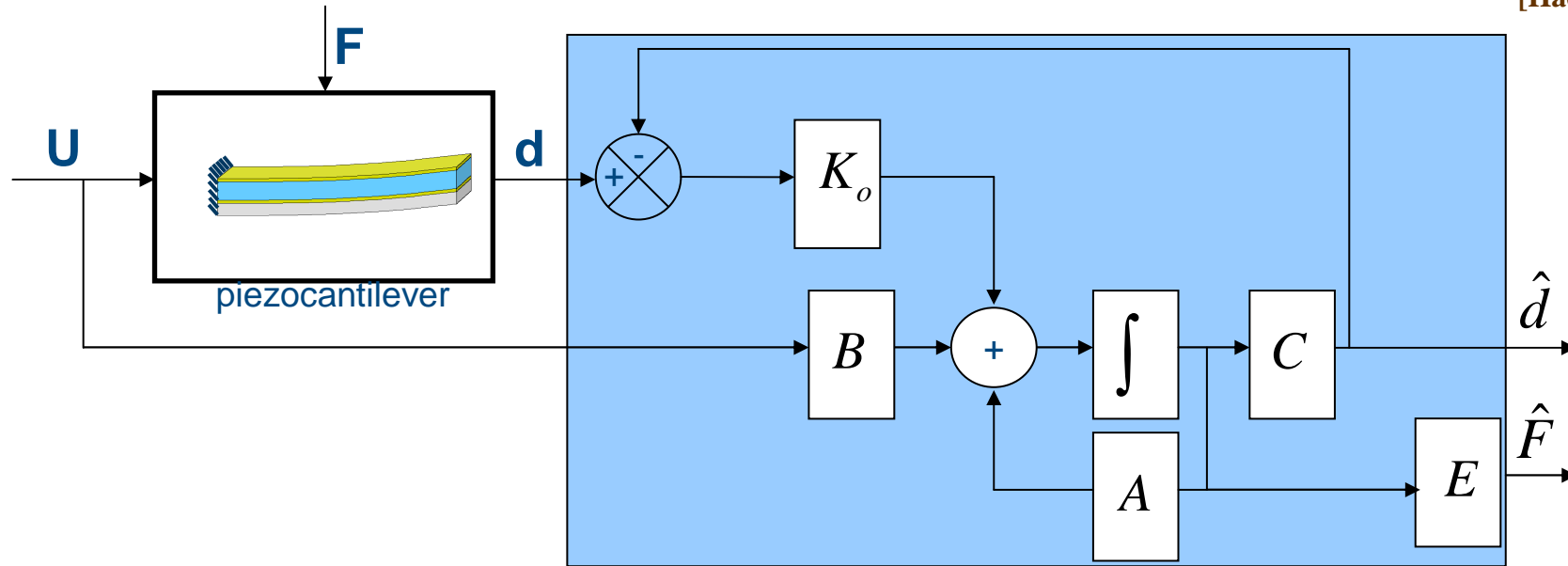
### C - Force measurement and control



### C - Force measurement and control

### Luenberger state observer

[Haddab, PhD00]



$$\frac{d}{dt} \begin{pmatrix} d \\ v \\ F \end{pmatrix} = \begin{pmatrix} 0 & 1 & 0 \\ a & b & 0 \\ 0 & 0 & 0 \end{pmatrix} \begin{pmatrix} d \\ v \\ F \end{pmatrix} + \begin{pmatrix} 0 \\ 0 \\ k \end{pmatrix} U$$

$$d = \begin{pmatrix} 1 & 0 & 0 \end{pmatrix} \begin{pmatrix} d \\ v \\ F \end{pmatrix}$$

**- Do not account nonlinearities (hysteresis and creep)**

**- Needs to impose dynamics**

$$\frac{d}{dt} \begin{pmatrix} \hat{d} \\ \hat{v} \\ \hat{F} \end{pmatrix} = \begin{pmatrix} 0 & 1 & 0 \\ a & b & 0 \\ 0 & 0 & 0 \end{pmatrix} \begin{pmatrix} \hat{d} \\ \hat{v} \\ \hat{F} \end{pmatrix} + \begin{pmatrix} 0 \\ 0 \\ k \end{pmatrix} U + \begin{pmatrix} K_1 \\ K_2 \\ K_3 \end{pmatrix} (d - \hat{d})$$

$$\hat{d} = \begin{pmatrix} 1 & 0 & 0 \end{pmatrix} \begin{pmatrix} \hat{d} \\ \hat{v} \\ \hat{F} \end{pmatrix}$$

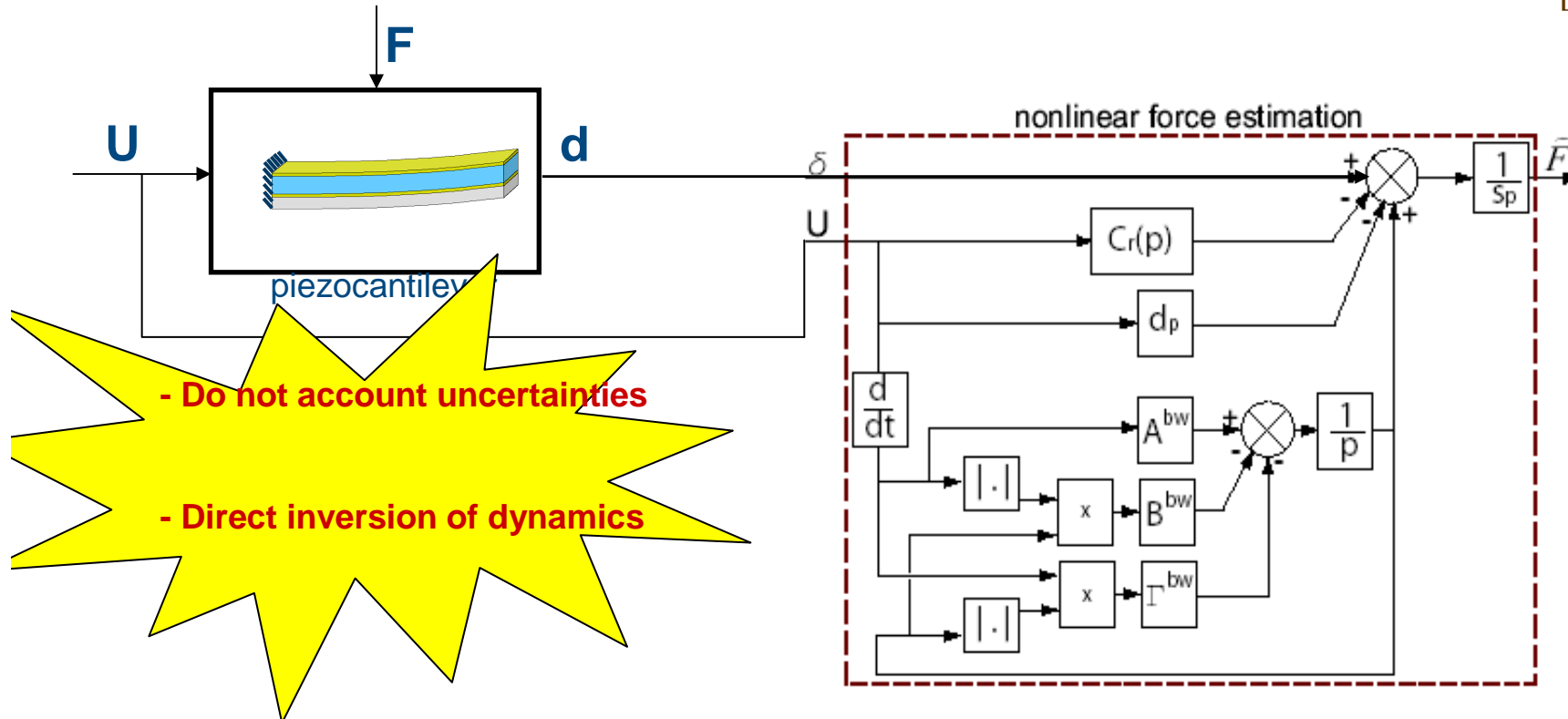
$$\hat{F} = \begin{pmatrix} 0 & 0 & 1 \end{pmatrix} \begin{pmatrix} \hat{d} \\ \hat{v} \\ \hat{F} \end{pmatrix}$$



C - Force measurement and control

Open-loop estimation

[AIM07]



- Do not account uncertainties

- Direct inversion of dynamics

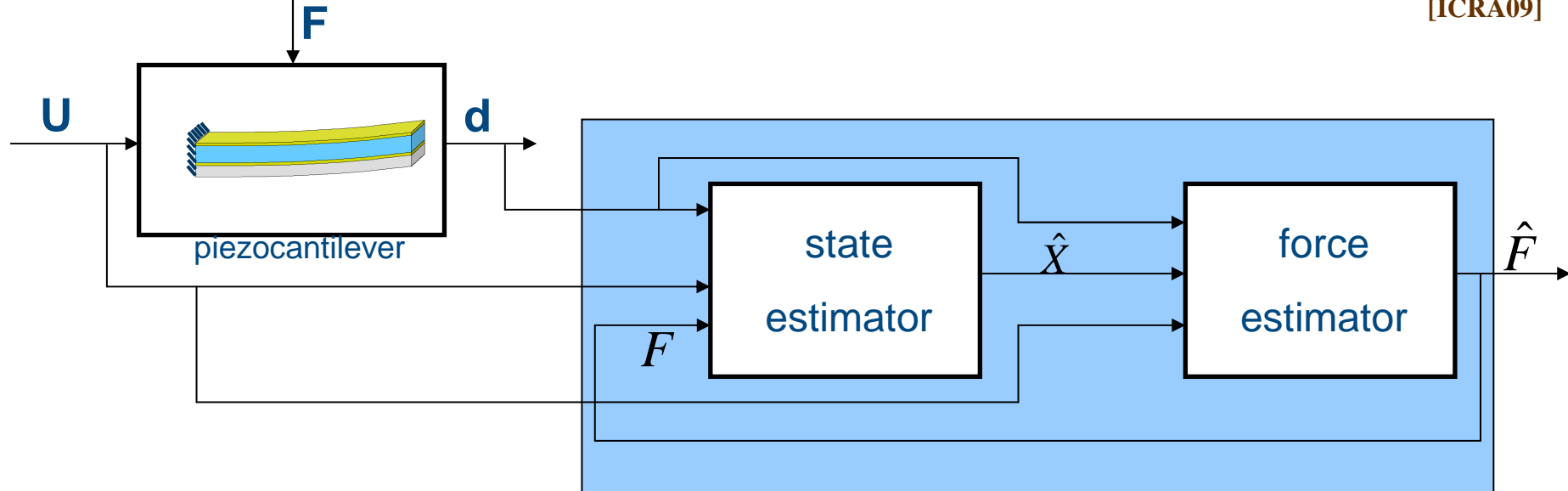
$$d = \Gamma(U) \cdot D(s) + C_r(s) \cdot U + s_p \cdot D(s) \cdot F$$

➔ 
$$\hat{F} = \frac{1}{s_p \cdot D(s)} \left[ d - \Gamma(U) \cdot D(s) + C_r(s) \cdot U \right]$$

C - Force measurement and control

Unknown Input Observer (UIO)

[ICRA09]



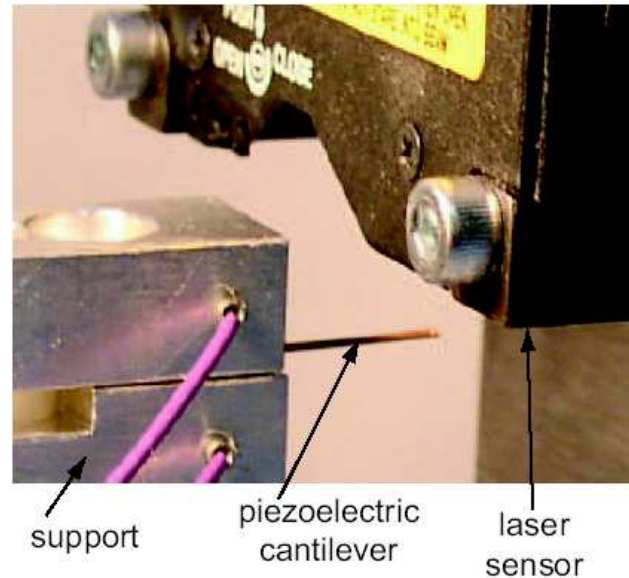
$$\begin{cases} \frac{dX}{dt} = A \cdot X + \Gamma(u, d) + B \cdot F \\ d = C \cdot X \end{cases}$$



$$\begin{cases} \frac{d\hat{X}}{dt} = A\hat{X} + \Gamma(u, d) + B \cdot \hat{F} + K(d - \hat{d}) \\ \hat{d} = C\hat{X} \end{cases}$$

$$\hat{F} = F_1 d + F_2 \frac{dd}{dt} + G_1 \hat{X} + G_2 \frac{d\hat{X}}{dt} + G_3 \Gamma(u, d)$$

### D – Limitation of using sensors

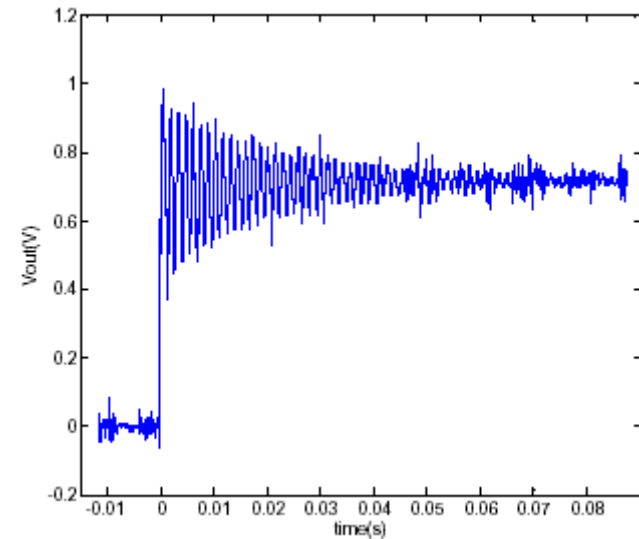
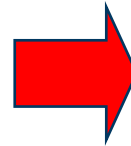
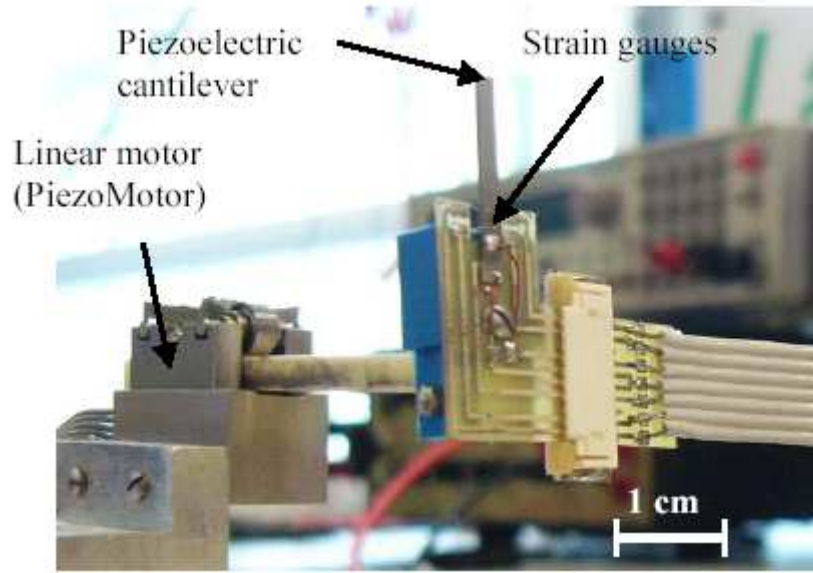


**- Accurate and high bandwidth sensors (optical sensors...):**

**→ expensive**

**→ large sizes (not convenient for packaged systems)**

**D – Limitation of using sensors**



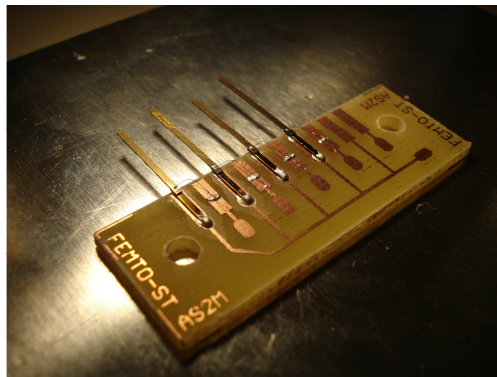
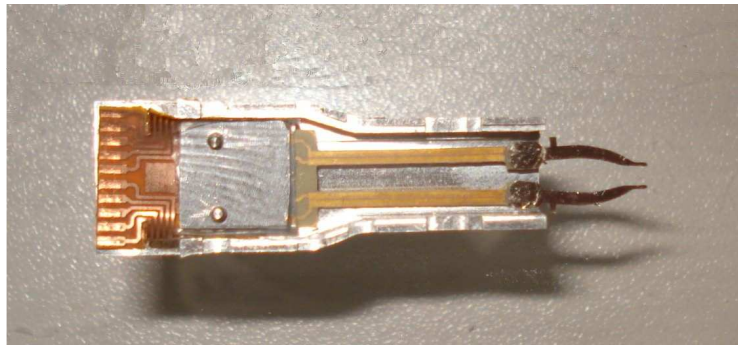
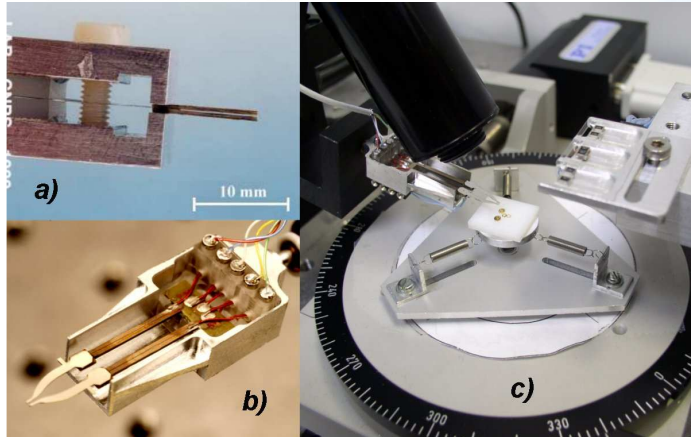
**- Embeddable sensors (strain gauge sensors):**

- noisy
- fragile

[Haddab et al, IFAC-Mech09]

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- **3 – Self sensing of piezocantilevers**
  - 3.1 Quasi-static free displacement self-sensing
  - 3.2 Dynamic displacement self-sensing
  - 3.3 Combined Force / displacement self-sensing



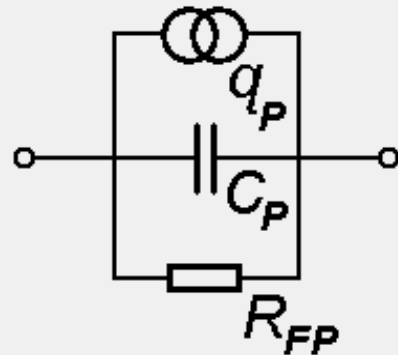
$$Q = \iint_A \sigma dx_1 dx_2$$

$$F_{ext} = 0 \rightarrow \text{Free displacement}$$

$$Q = \frac{4wh\epsilon_{33}}{3d_{31}L} \left( 1 + \frac{d_{31}^2}{4s_{11}^E \epsilon_{33}^S} \right) \delta =$$

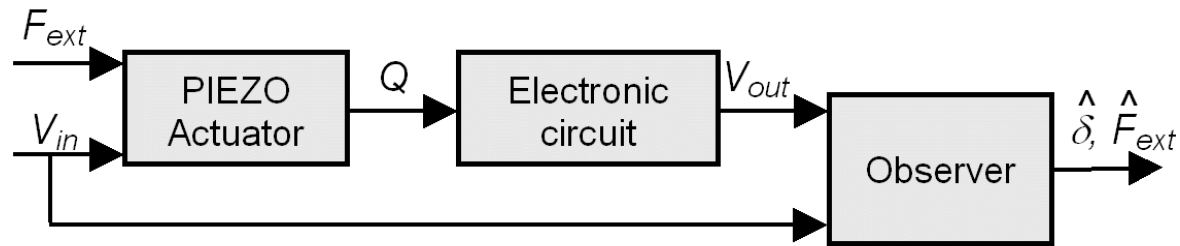
$$= \alpha \delta$$

$$F_{ext} \neq 0 \rightarrow \text{Force/Displacement}$$



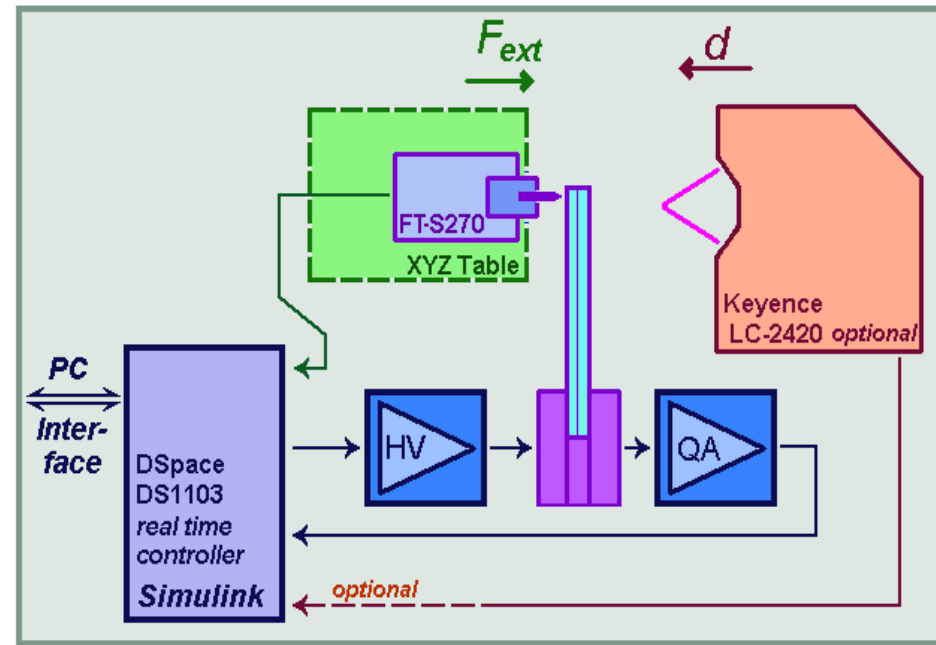
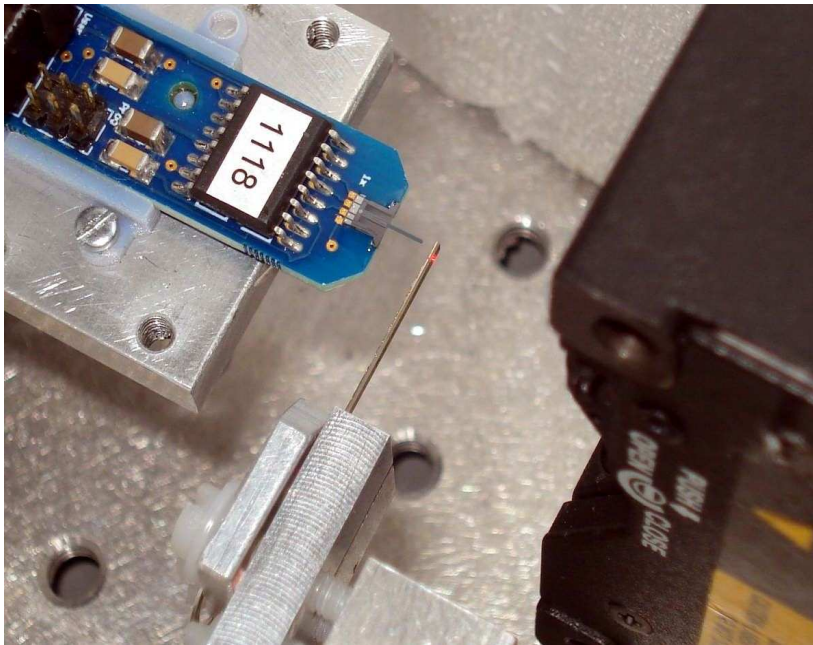
$$Q = -3e_{31}s_{11} \frac{L^2}{h^2} F_{ext} + \frac{4Lw\epsilon_{33}V_{in}}{h} =$$

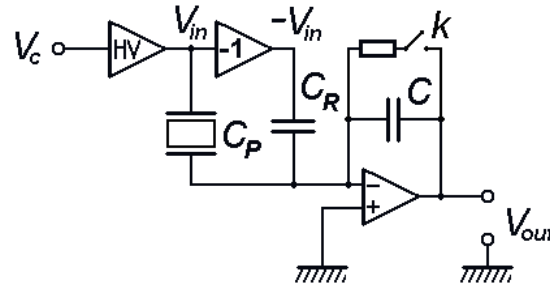
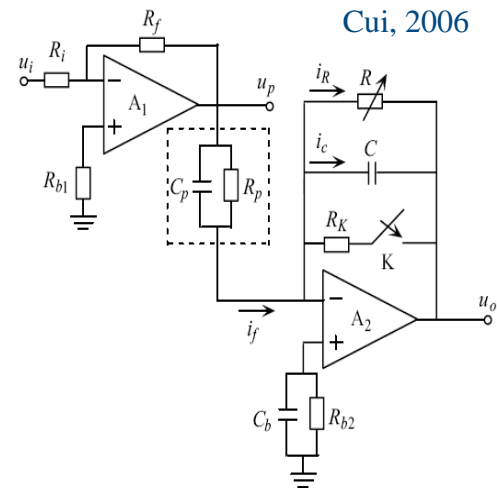
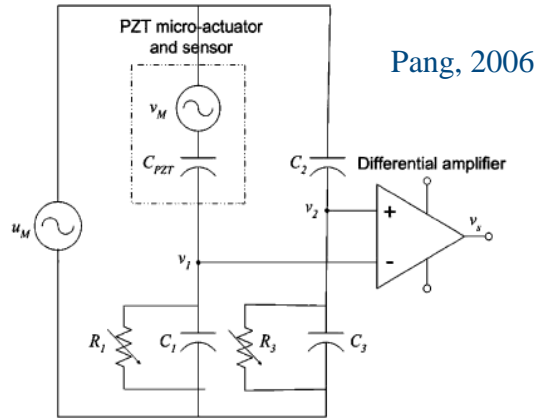
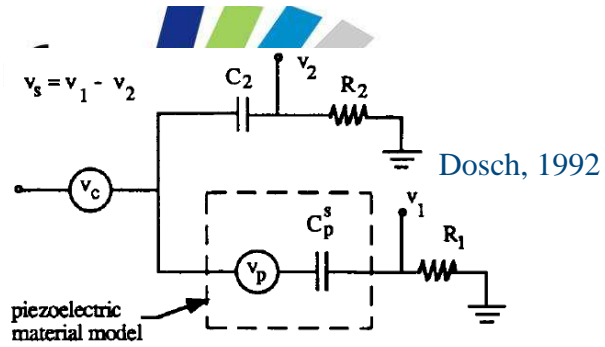
$$= \beta F_{ext} + C_P V_{in}$$



### Sensorless method

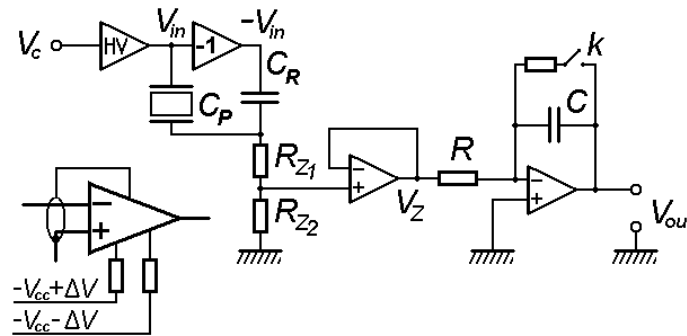
Observer may be further used in a closed loop control



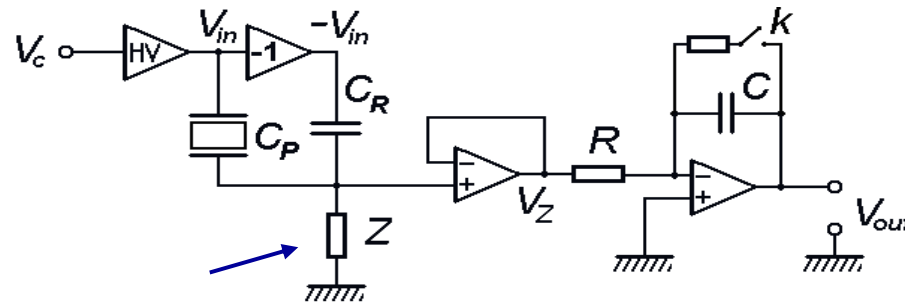


## Current integrators.

Direct charge conv.



Resistive divider



Impedance (dynamic)

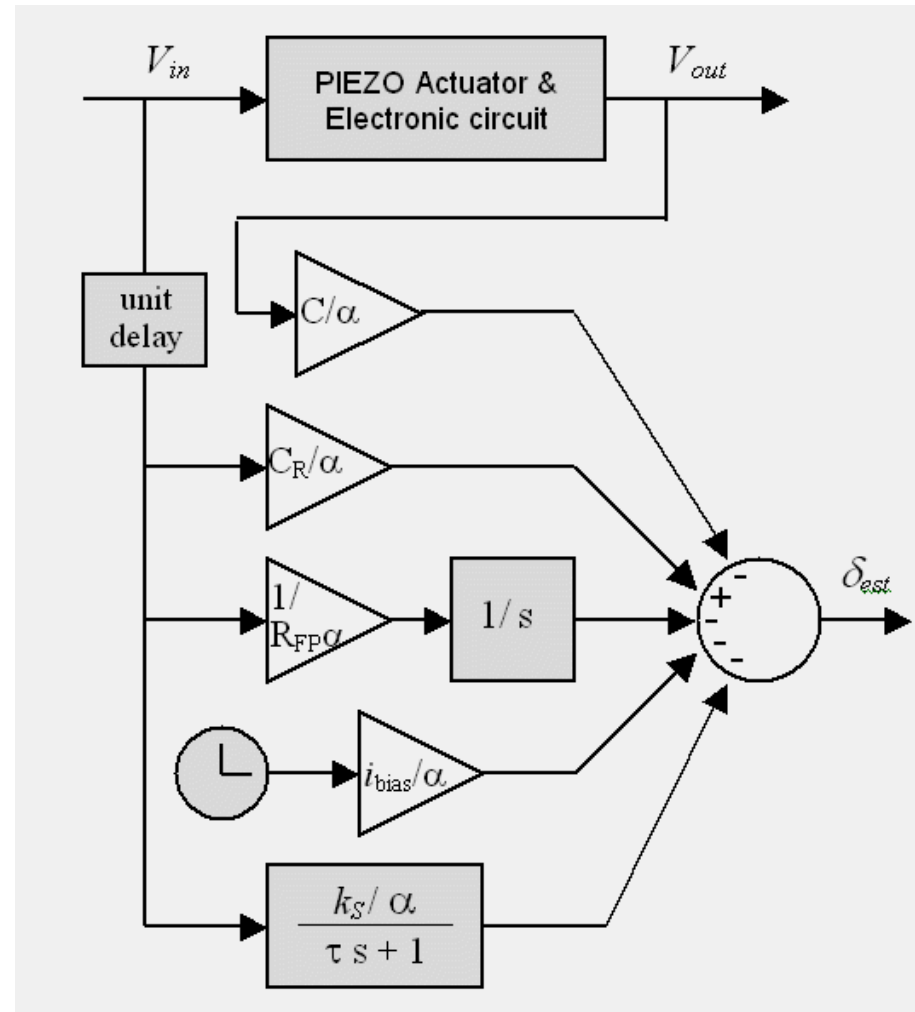


## Quasi-static free displacement self-sensing OBSERVER

$$Q = -C_R V_{in} + \alpha \delta$$

$$V_{out} = \frac{C_R}{C} V_{in} - \frac{\alpha \delta + Q_{DA}}{C} - \frac{1}{C} \int \frac{V_{in}(t)}{R_{FP}} dt - \frac{1}{C} \int i_{BIAS}(t) dt$$

$$\delta_{est} = -\frac{C}{\alpha} V_{out} - \frac{Q_{DA}(V_{in}, t)}{\alpha} + \frac{C_R}{\alpha} V_{in} - \frac{1}{R_{FP} \alpha} \int V_{in}(t) dt - \frac{1}{\alpha} \int i_{BIAS}(t) dt$$



Connus:  $C$  et  $C_R$

Inconnus:  $\alpha$ ,  $i_{BIAS}$ ,  $R_{FP}$  et  $Q_{DA}$

$$F_{ext}=0$$

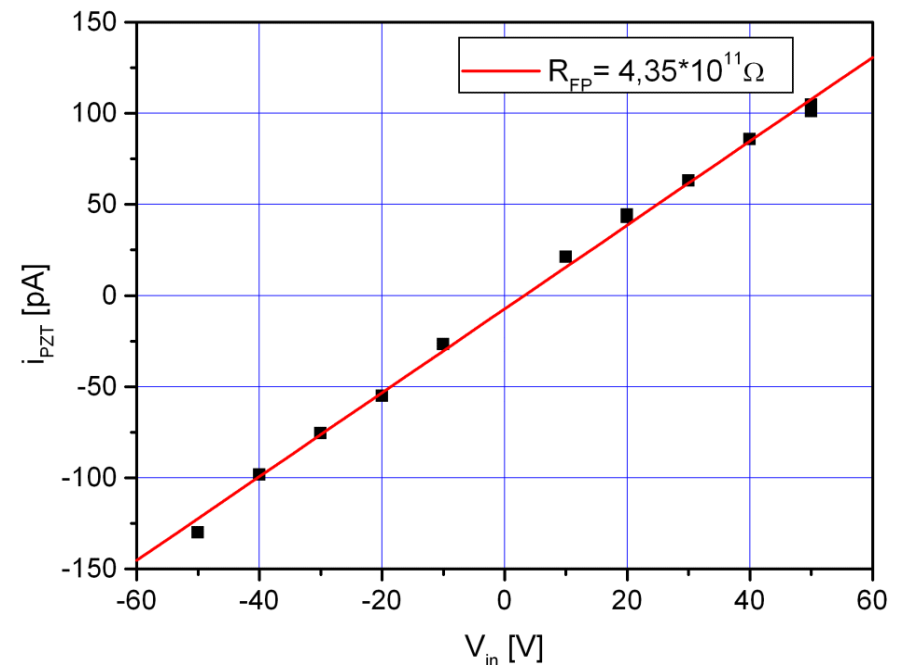
Etapes:

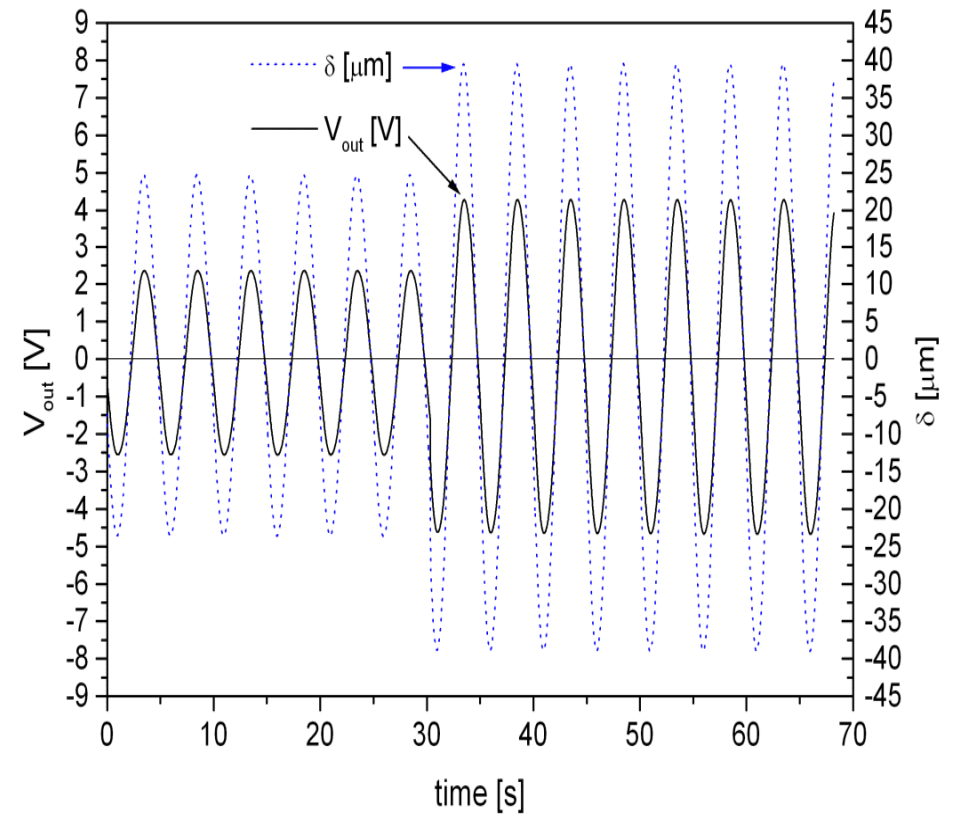
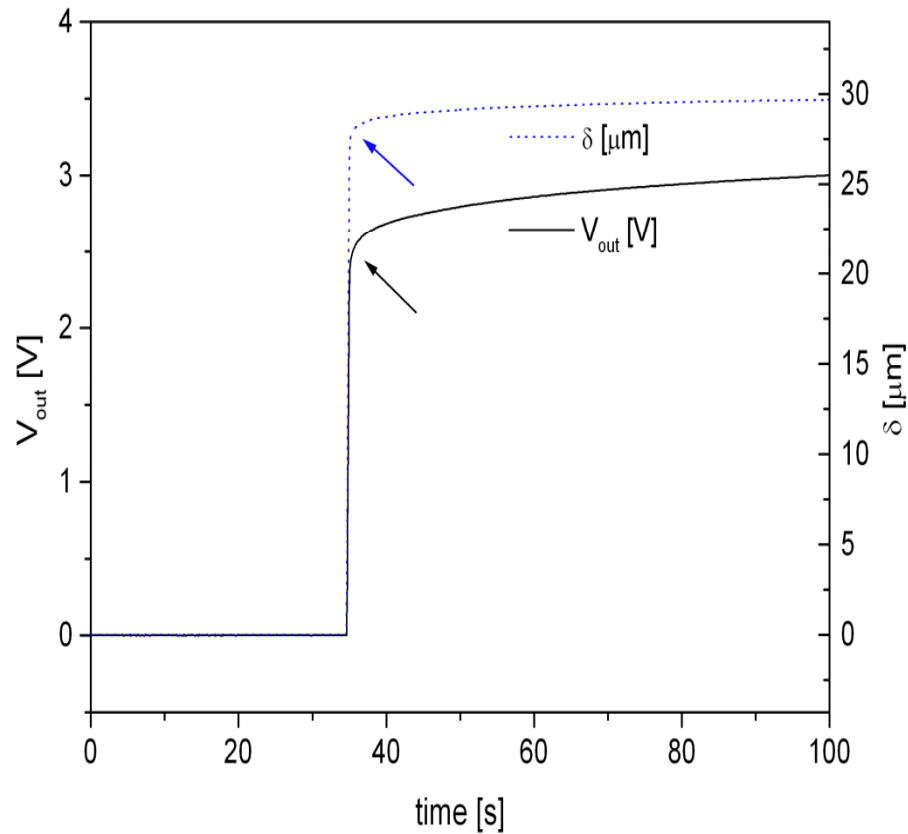
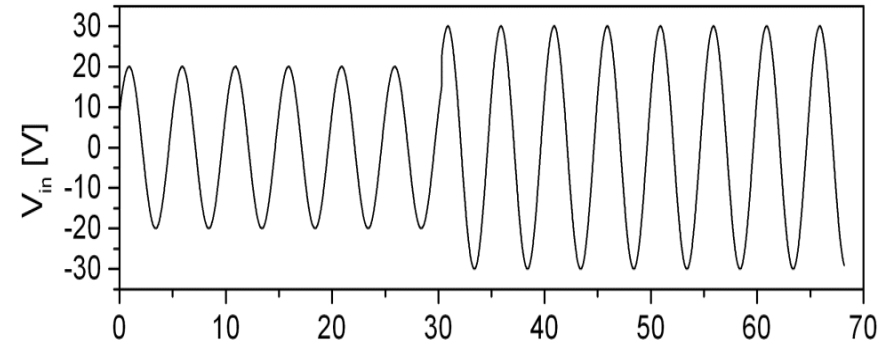
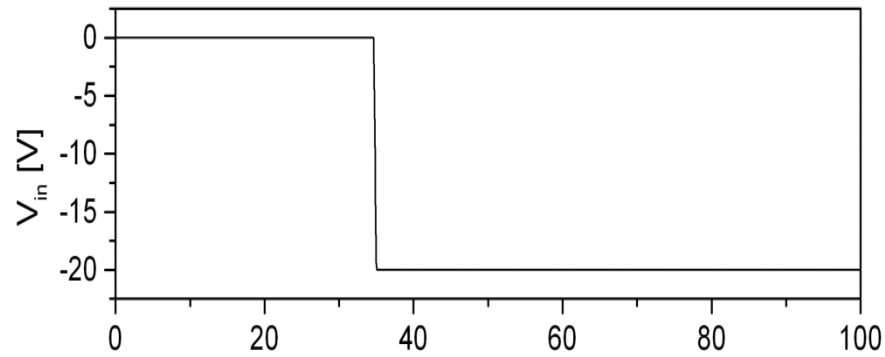
1) Courant polarisation  $i_{BIAS}$ :  $V_{in}=0 \rightarrow$  taux de variation  $V_{out}$

2) Resistance de fuite  $R_{FP}$ : echelon  $V_{in} \neq 0 \rightarrow$  derive  $V_{out}$  apres  $> 1000$  s.

3) Coeff. de déplacement  $\alpha$  [C/m]:  
echelon  $V_{in}$  ou signal sinusoidal

$$\rightarrow \alpha = (-C V_{out} + C_R V_{in}) / \delta$$





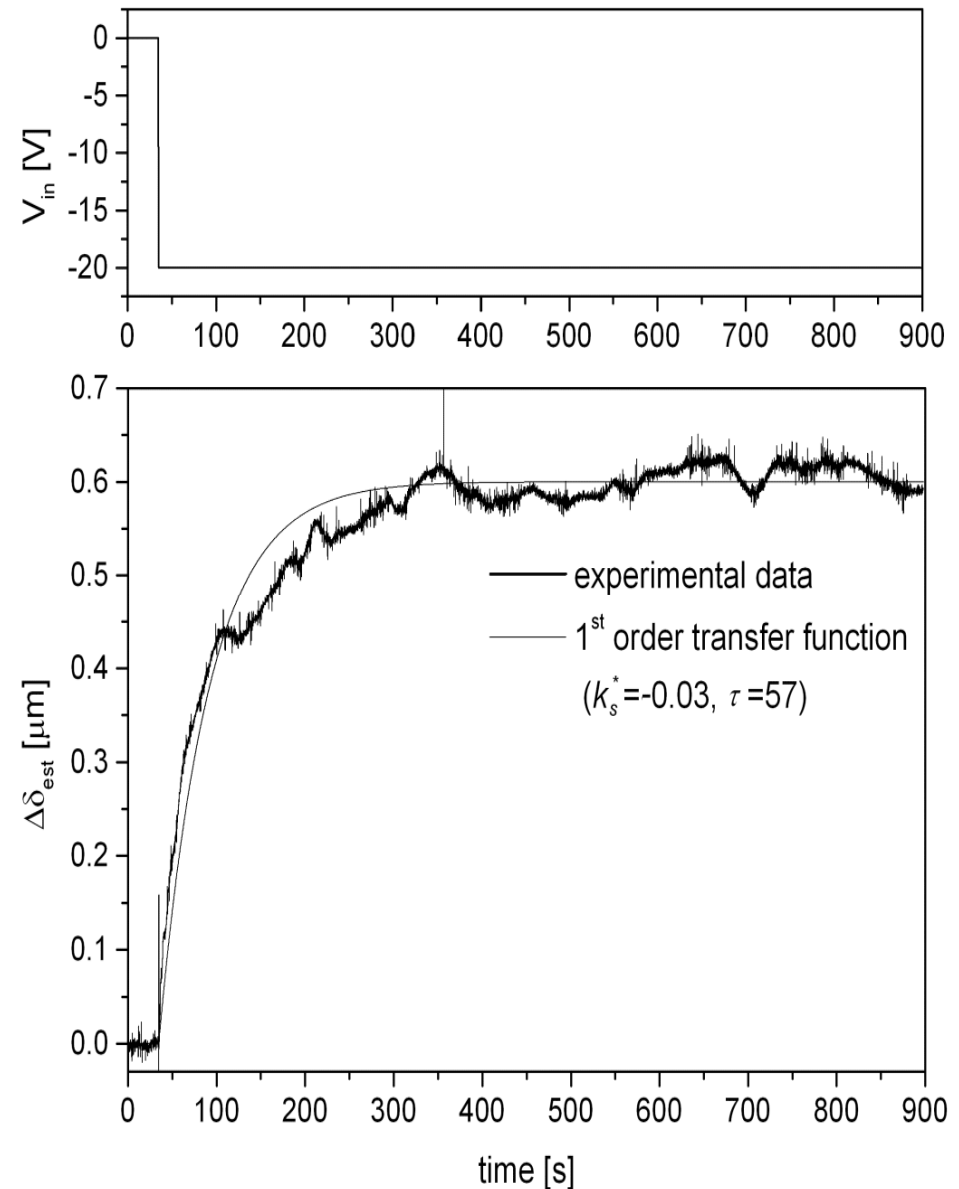
4) Absorption dielectrique  $Q_{DA}$   
identification fonction de transfer  
de premier ordre.

$$\Delta\delta_{est} = \delta_{est} - \delta$$

$$\rightarrow \Delta\delta_{est}(s) = Q_{DA}^*(s)V_{in}(s)$$

$$Q_{DA}^*(s) = \frac{Q_{DA}(s)}{\alpha} = \frac{k_s^*}{\tau s + 1}$$

$$k_s^* = k_s / \alpha$$



Matlab Simulink:

$\alpha = -10.05e-9;$

$C = 47e-9;$

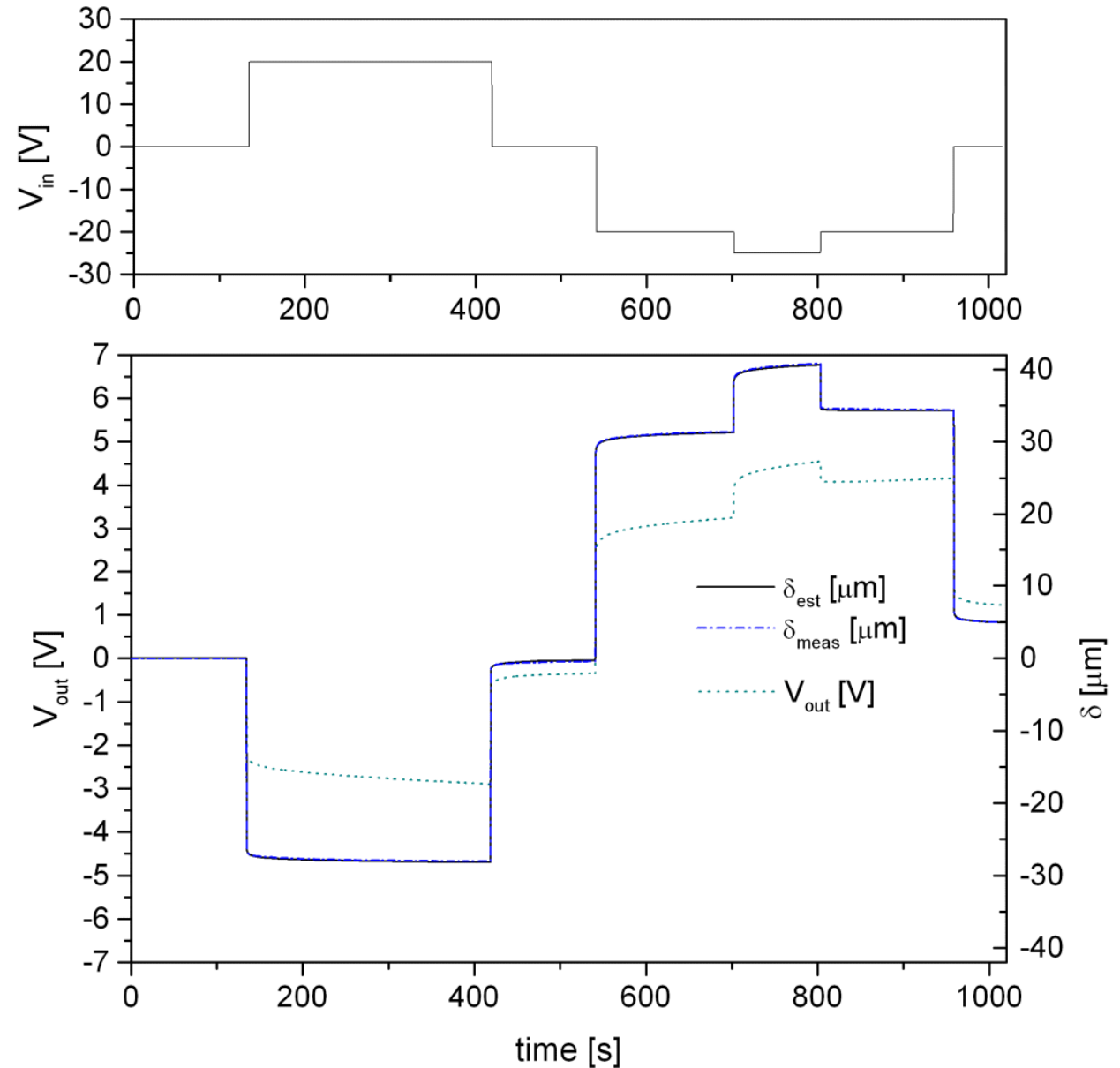
$C_r = 8.2e-9;$

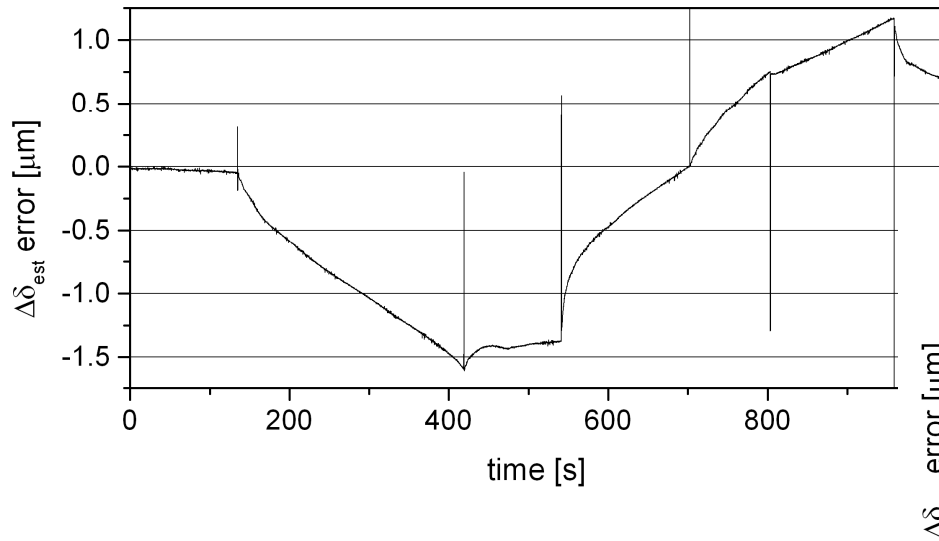
$R_{fp} = 0.435e12;$

$i_{bias} = -1.7e-12;$

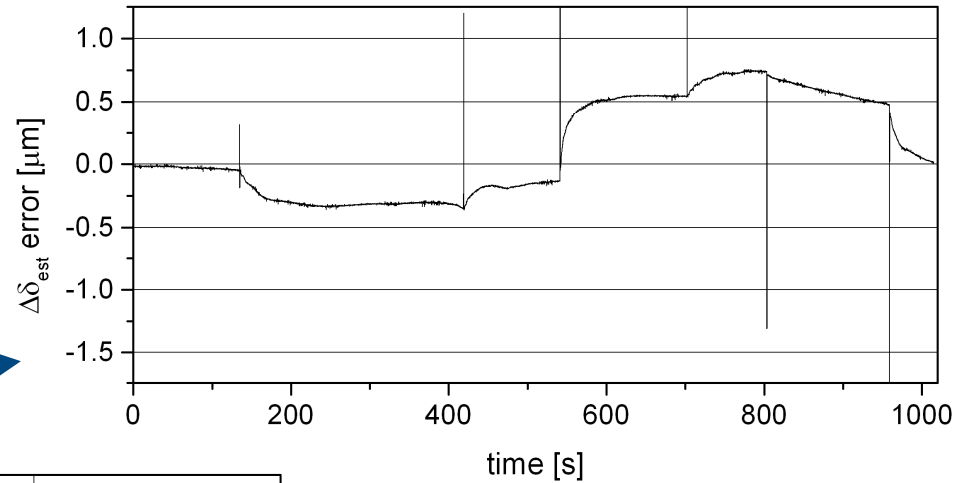
$\tau = 57;$

$k_s = 3.02e8;$

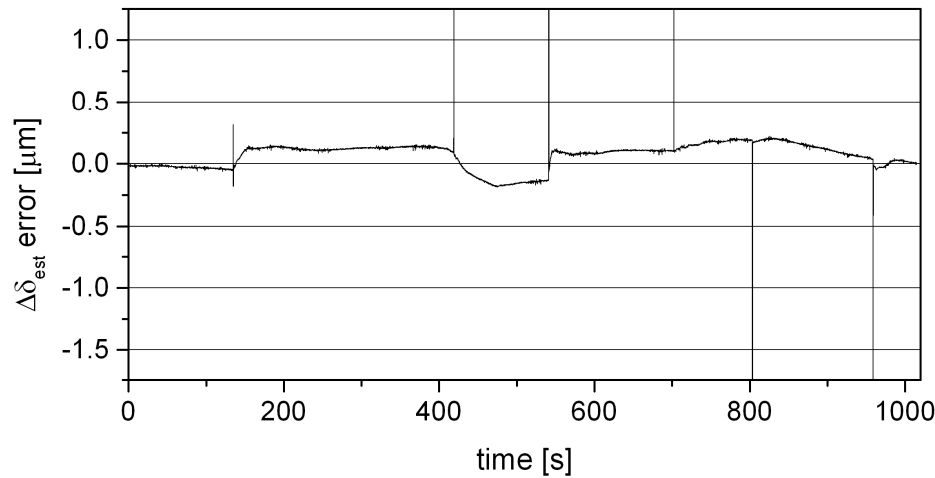




sans compensation  
erreur 2.75  $\mu\text{m}$

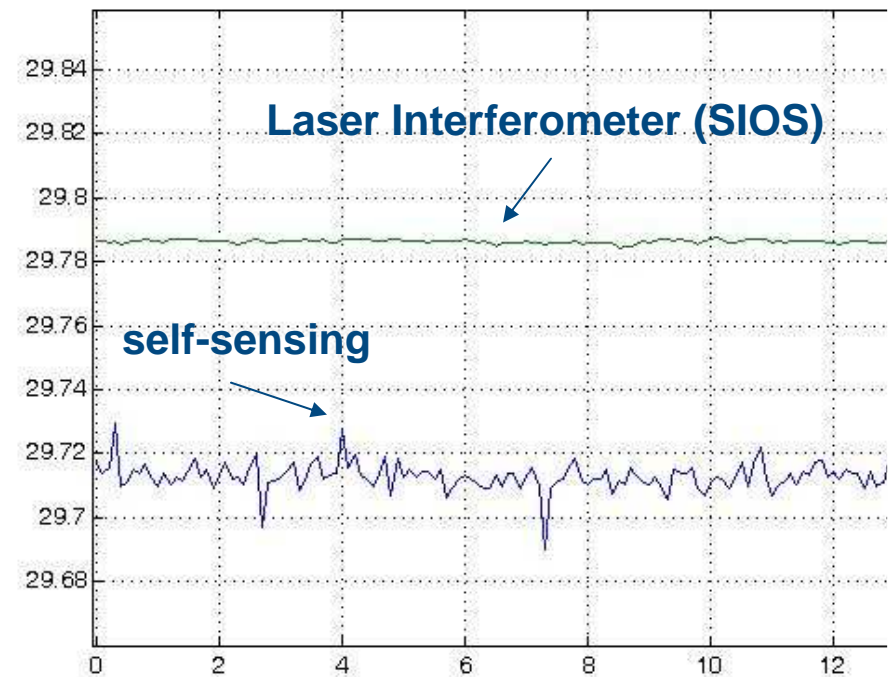
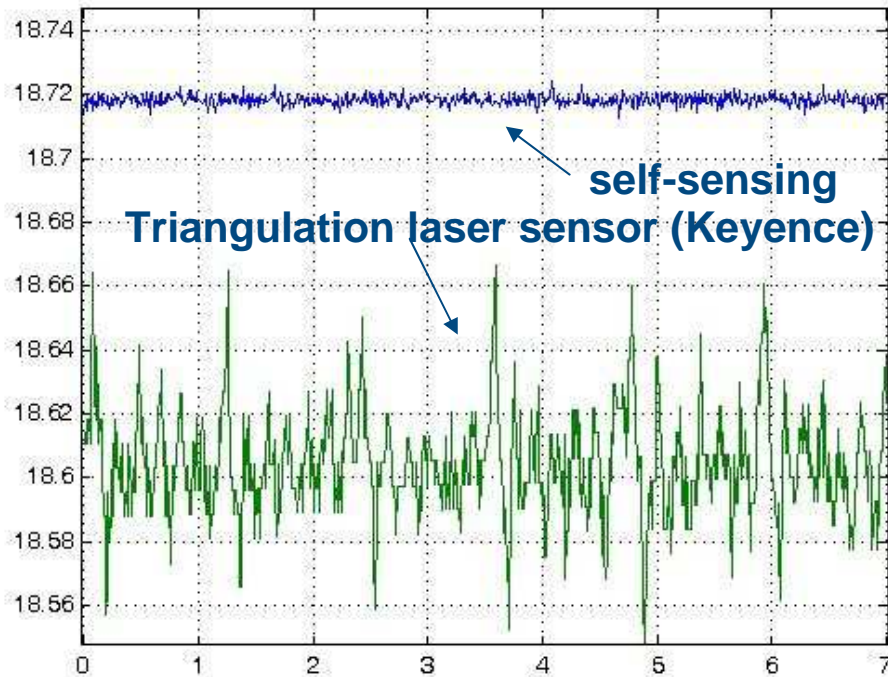


compensation  $R_{FP}$  erreur 1.05  $\mu\text{m}$



compensation  
 $R_{FP}$  et  $Q_{DA}$  :  
erreur 0.38  $\mu\text{m}$   
**0.55%**



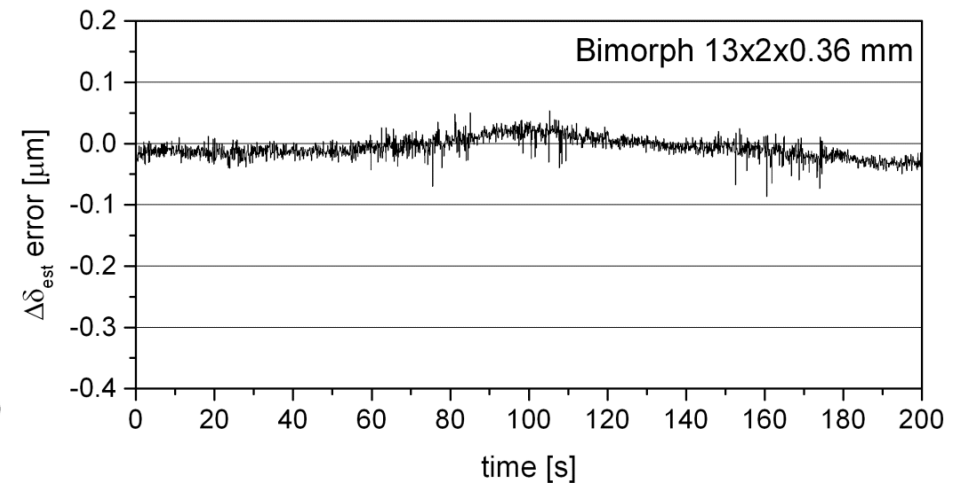
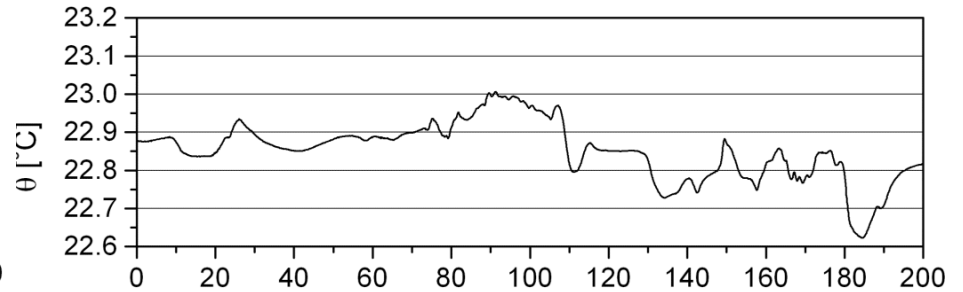
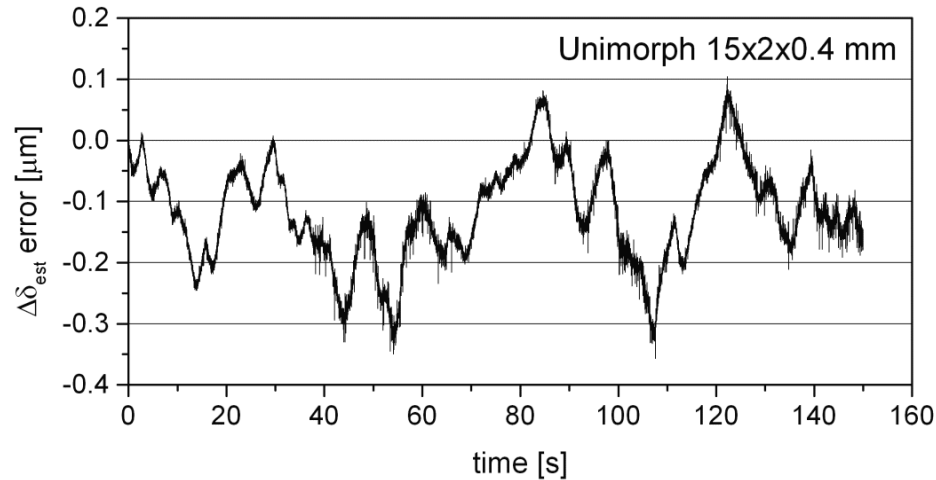
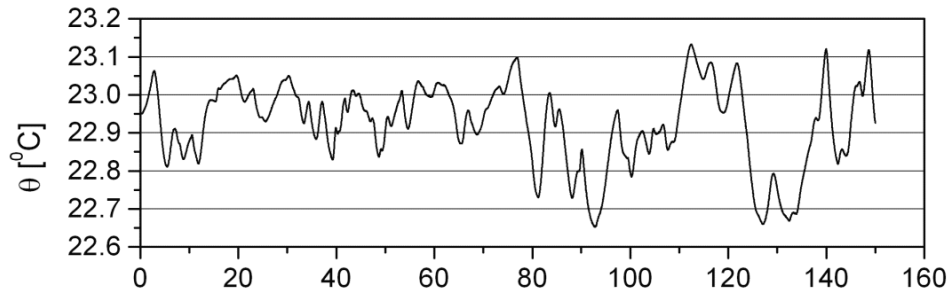


Noise measurement

**16.7 nm (RMS)** Keyence

**2 nm (RMS)** self-sensing (temperature isolated)

**0.55 nm (RMS)** SIOS



Self-sensing Error due to ambient temperature variations

Unimorph cantilever  
 $\sim 1\mu\text{m}/^\circ\text{C}$

Bimorph cantilever  
 $\sim 0.2\mu\text{m}/^\circ\text{C}$



### 3. Self-Sensing of Piezoelectric Actuators

#### 3.2 Dynamic displacement self-sensing

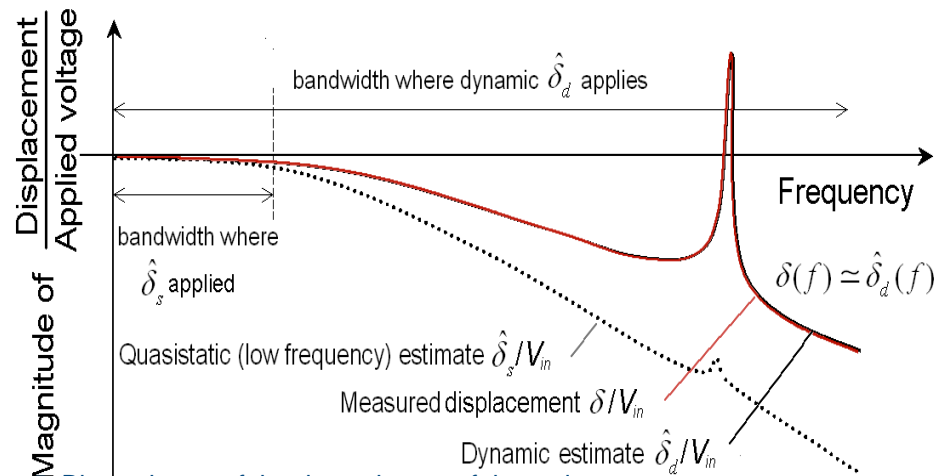
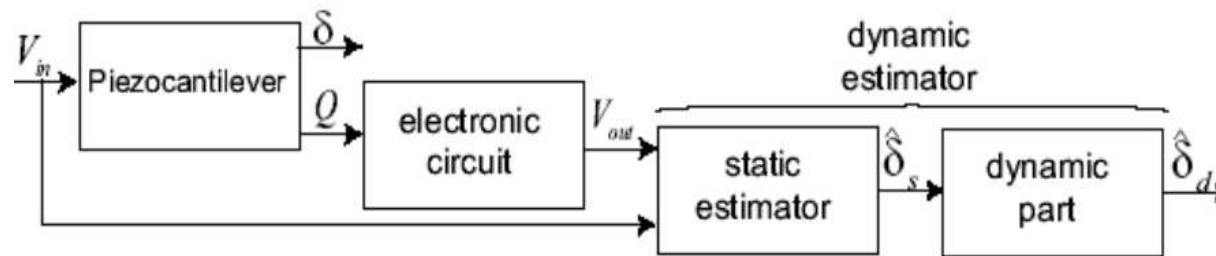
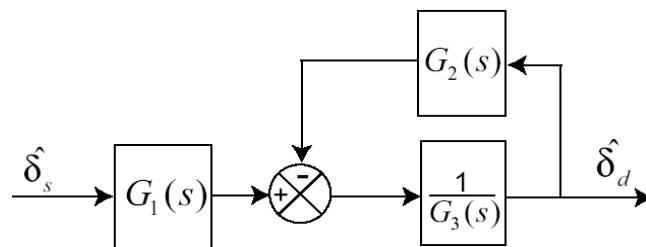


Figure 5. Bloc-scheme of the dynamic part of the estimator.

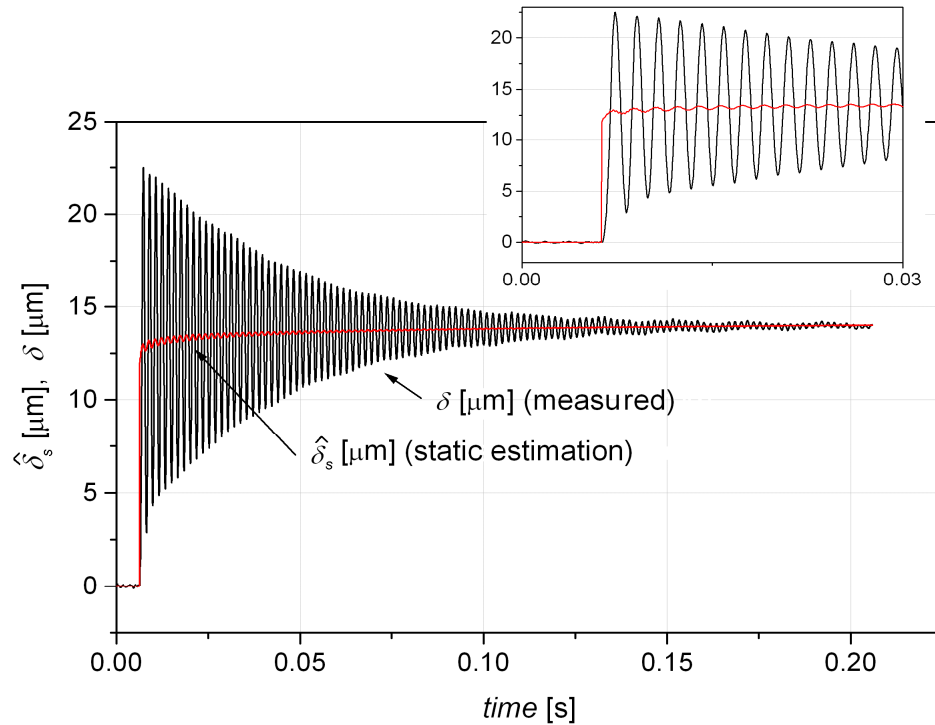
Static (low frequency) Self Sensing and required dynamic self-sensing intended to superpose real (externally measured) displacement.



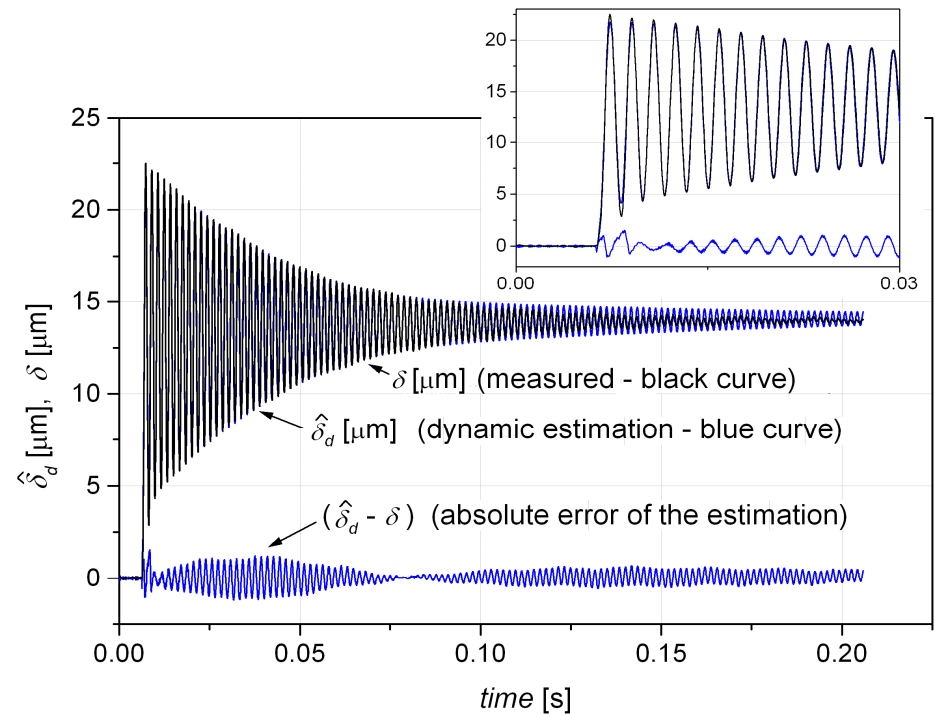
Principle scheme of the dynamic self-sensing technique.



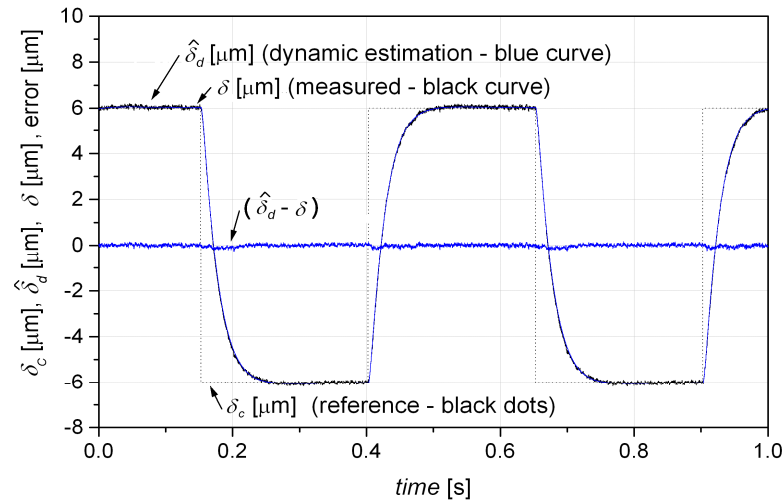
Dynamic Estimator – Reverse Multiplicative form



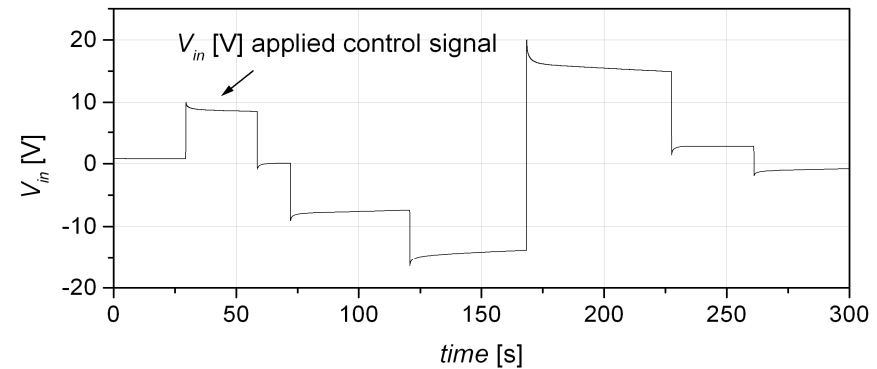
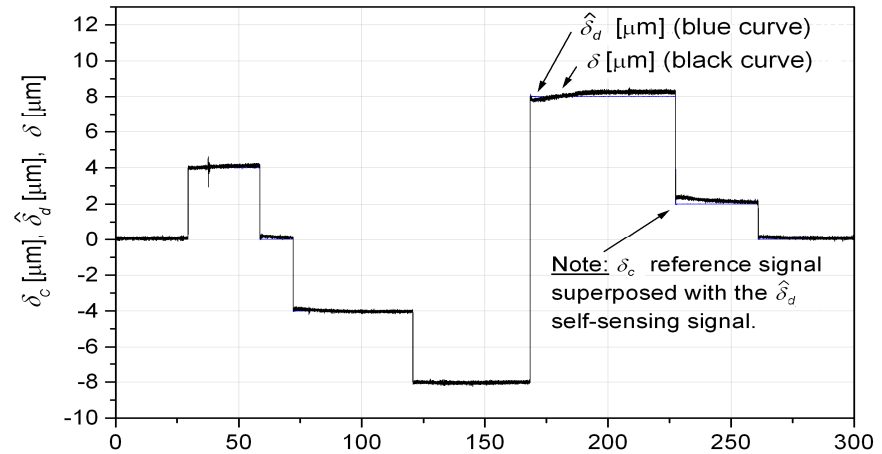
Result with static self-sensing (step input of 20V).



Result with dynamic self-sensing.



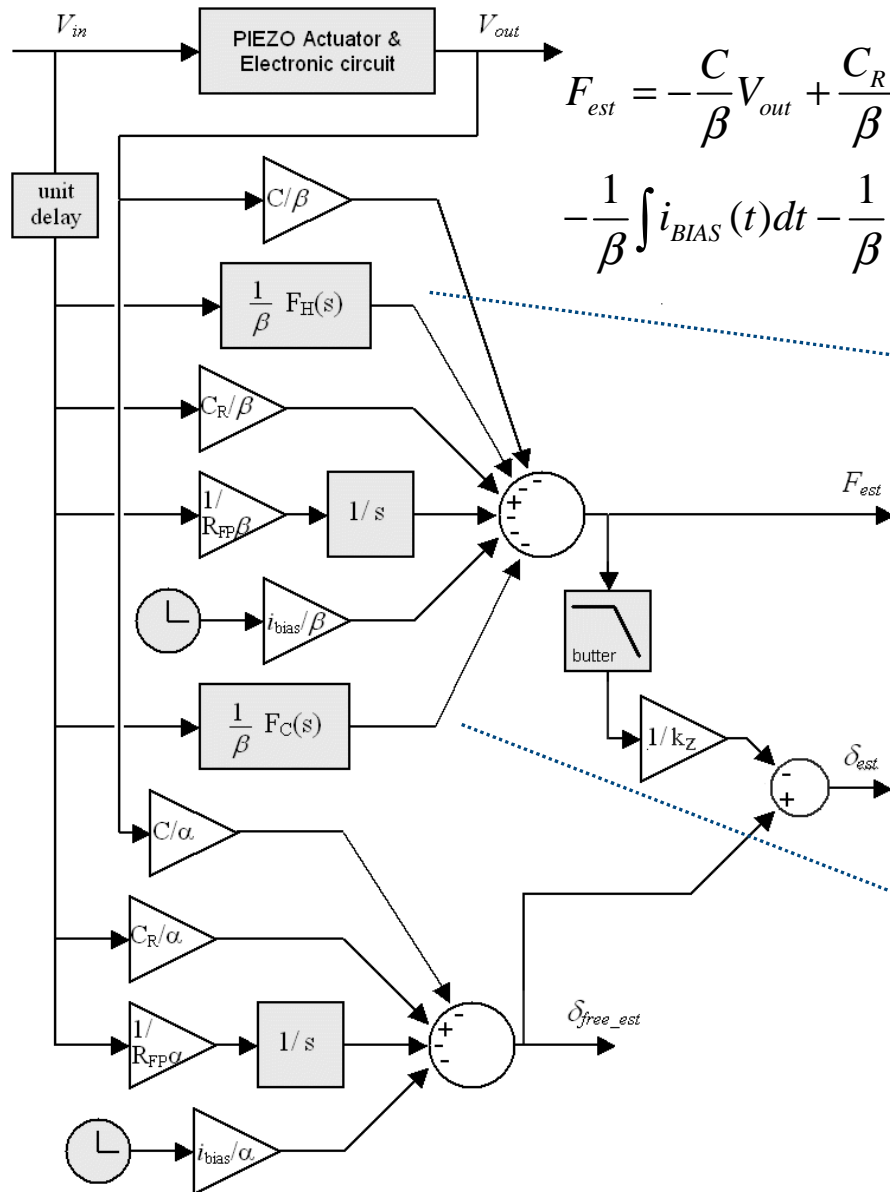
Step response of the closed-loop system.  
Settling time : 30 ms  
Dynamic error: 5%



Complete short and long term response of the closed-loop system.

### 3. Self-Sensing of Piezoelectric Actuators

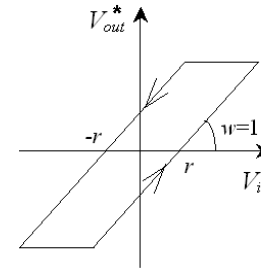
#### 3.3 Combined Force / Displacement self-sensing



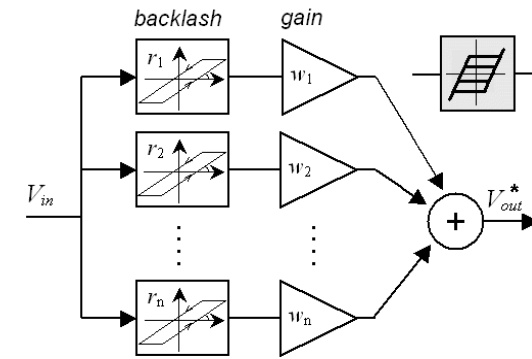
$$F_{est} = -\frac{C}{\beta}V_{out} + \frac{C_R}{\beta}V_{in} - \frac{1}{R_{FP}\beta} \int V_{in}(t)dt - \frac{1}{\beta} \int i_{BIAS}(t)dt - \frac{1}{\beta} F_C(s) \cdot V_{in} - \frac{1}{\beta} F_H(s) \cdot V_{in}$$

Force and displacement observation

$$\delta_{est} = \delta_{free\_est} - F_{est} / k_Z$$



a)

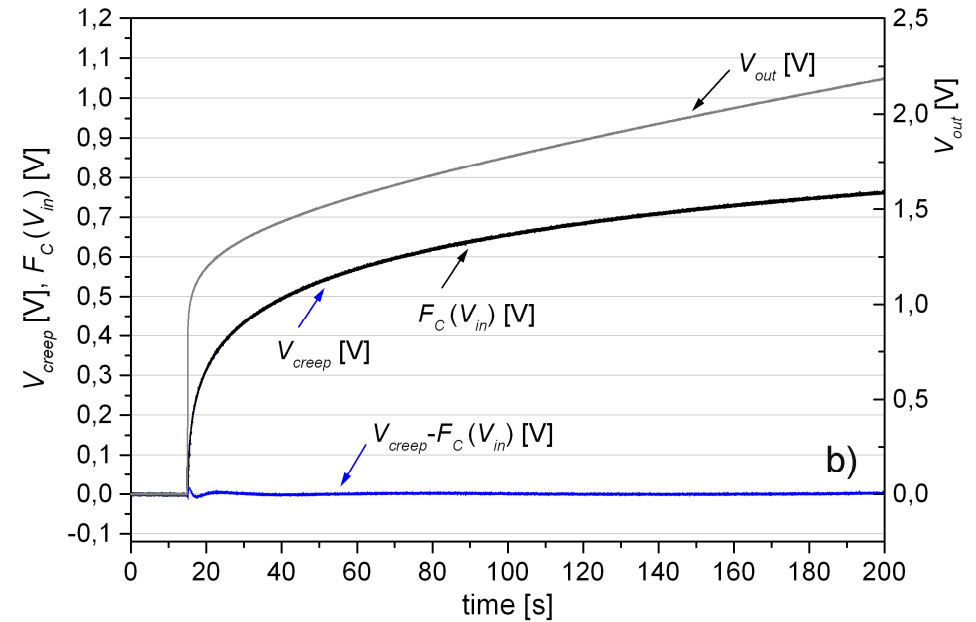
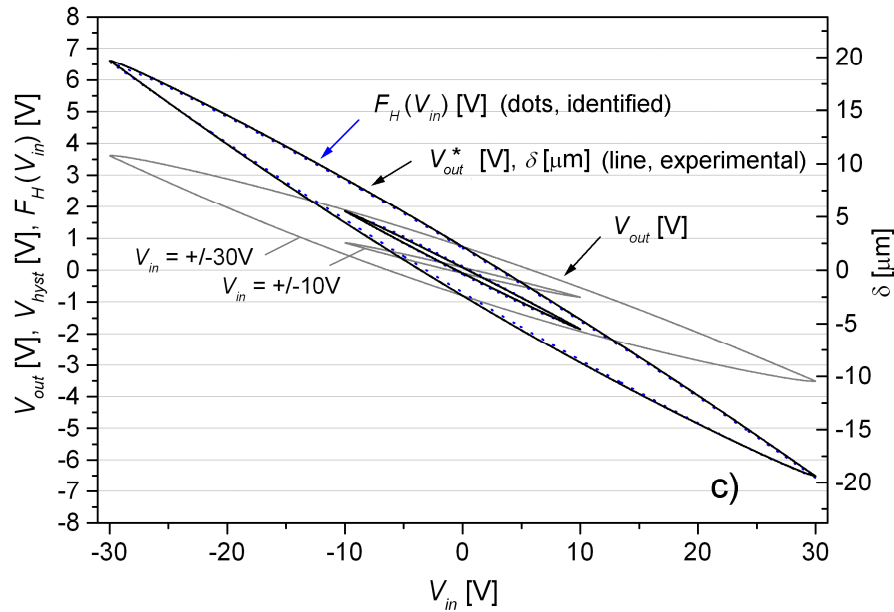
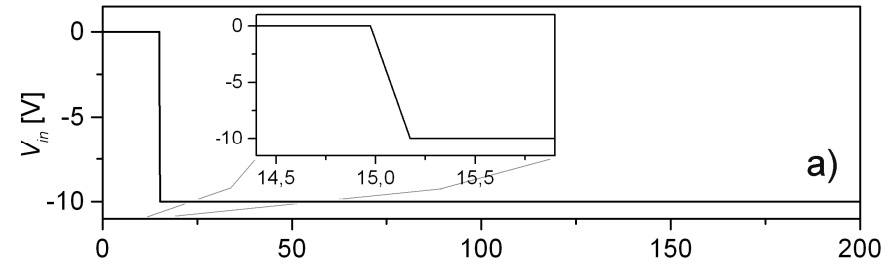
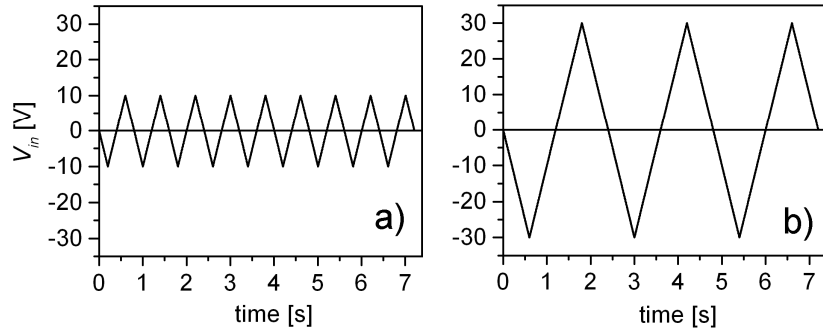


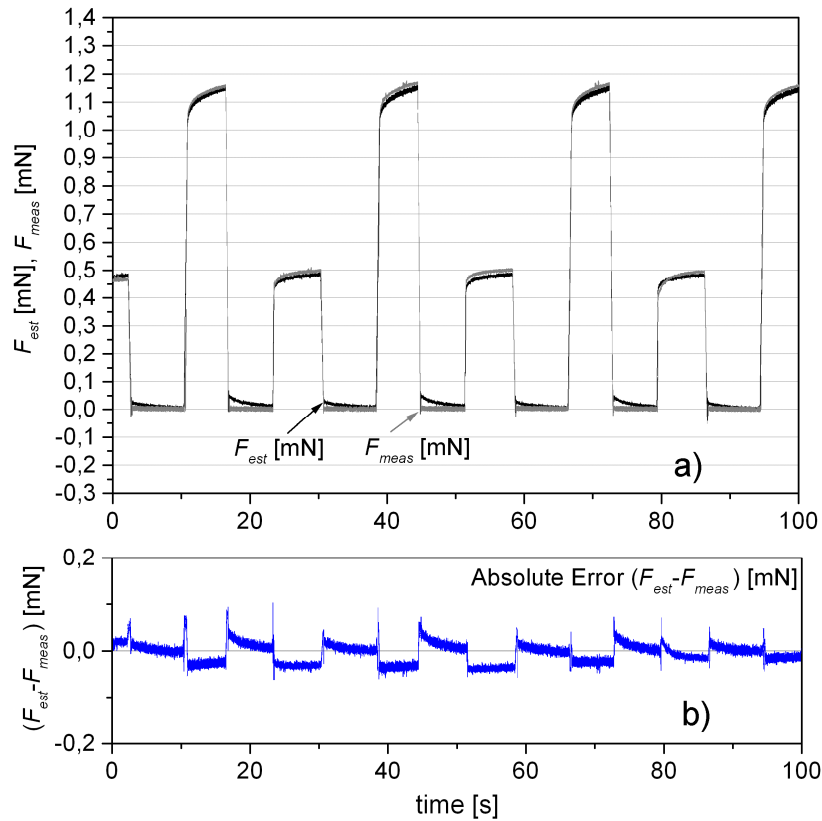
b)

Hysteresis Model a) The play operator; b) Prandtl-Ishlinskii (PI) hysteresis model.

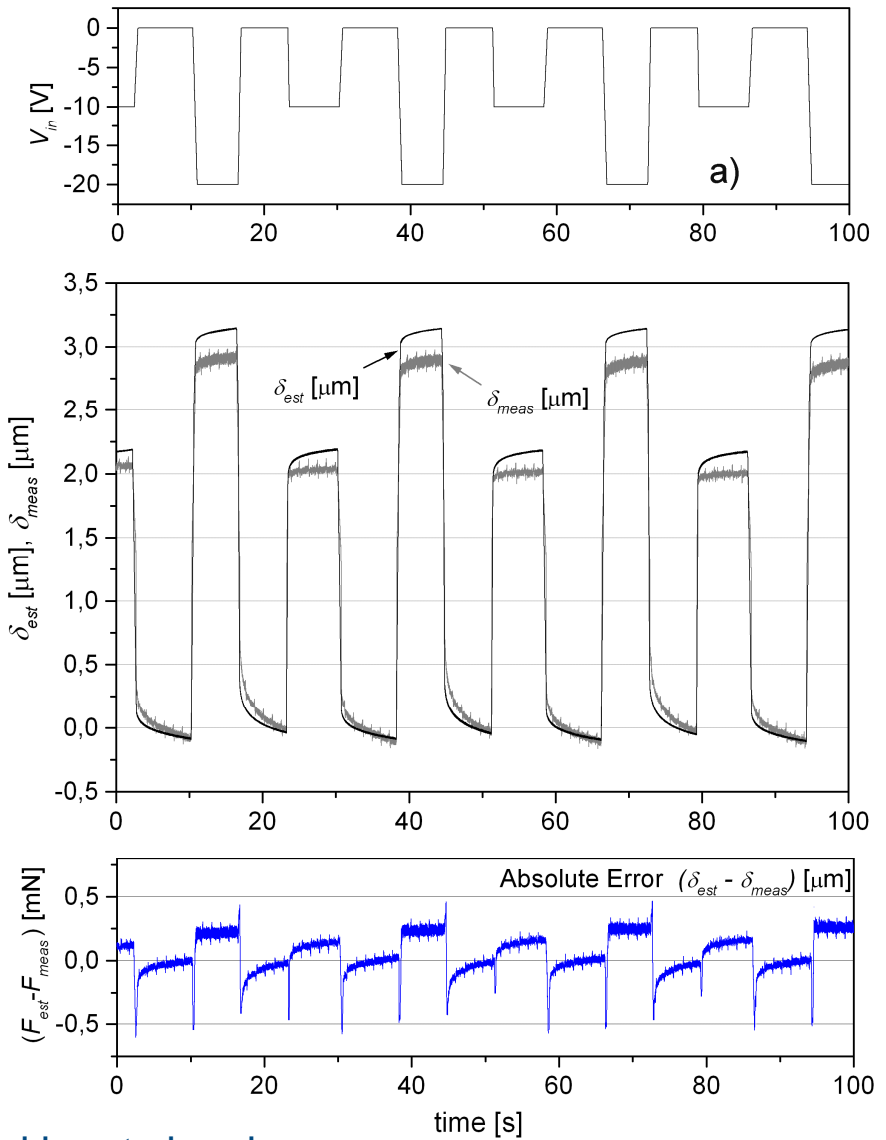
$$F_C(s) = \frac{V_{creep}(s)}{V_{in}(s)} = \frac{a_0s^4 + a_1s^3 + a_2s^2 + a_3s^1 + a_4}{s^4 + b_1s^3 + b_2s^2 + b_3s^1 + b_4}$$

Creep TF Model





a) Measured and estimated force.  
b) Absolute error (force).



a) Applied input signal  
b) Measured and estimated tip displacement.  
c) Absolute error (displacement)

- 1 – FEMTO-ST and SAMMI group activities
- 2 – Observer techniques applied to piezocantilevers
- 3 – Self sensing of piezocantilevers

THANK YOU!